



# RADIO TEST REPORT

**Test Report No. : 33BE0184-HO-04-A-R1**

**Applicant** : Panasonic Corporation of North America  
**Type of Equipment** : Wireless Speaker System  
**Model No.** : SC-NE1  
**FCC ID** : ACJ-SC-NE1  
**Test regulation** : FCC Part 15 Subpart C: 2012  
**Test Result** : Complied

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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.
6. This report is a revised version of 33BE0184-HO-04-A. 33BE0184-HO-04-A is replaced with this report.

**Date of test:** October 16 to November 28, 2012

**Representative test engineer:**

Hironobu Ohnishi  
Engineer of WiSE Japan,  
UL Verification Service

**Approved by:**

Takahiro Hatakeda  
Leader of WiSE Japan,  
UL Verification Service



NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation.  
\*As for the range of Accreditation in NVLAP, you may refer to the WEB address,  
<http://www.ul.com/japan/jpn/pages/services/emc/about/mark1/index.jsp#nvlap>

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**Head Office EMC Lab.**

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13-EM-F0429

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## **SECTION 1: Customer information**

Company Name : Panasonic Corporation \*  
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Telephone Number : +81-50-3487-3469  
Facsimile Number : +81-6-6906-8800  
Contact Person : Kazuo Taniguchi

\*Panasonic Corporation is on behalf of the applicant: Panasonic Corporation of North America.

## **SECTION 2: Equipment under test (E.U.T.)**

### **2.1 Identification of E.U.T.**

Type of Equipment : Wireless Speaker System  
Model No. : SC-NE1  
Serial No. : Refer to Clause 4.2  
Rating : AC 120V  
Receipt Date of Sample : October 16, 2012  
Country of Mass-production : Malaysia  
Condition of EUT : Production prototype  
(Not for Sale: This sample is equivalent to mass-produced items.)  
Modification of EUT : No Modification by the test lab

### **2.2 Product Description**

#### **Radio Specification**

Radio Type : Transceiver  
Frequency of Operation : 2402-2480MHz  
Modulation : FHSS  
Power Supply (inner) : DC 3.3V  
Antenna type : Internal Antenna  
Antenna Gain : 4.85dBi

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## **SECTION 3: Test specification, procedures & results**

### **3.1 Test Specification**

Test Specification : FCC Part 15 Subpart C: 2012, final revised on August 13, 2012 and effective September 12, 2012

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators  
Section 15.207 Conducted limits  
Section 15.247 Operation within the bands 902-928MHz,  
2400-2483.5MHz, and 5725-5850MHz

\*The EUT complies with FCC Part 15 Subpart B: 2012, final revised on August 13, 2012 and effective September 12, 2012.

### **3.2 Procedures and results**

Item	Test Procedure	Specification	Worst Margin	Results	Remarks
Conducted Emission	FCC: ANSI C63.4:2003 7. AC powerline conducted emission measurements IC: RSS-Gen 7.2.4	FCC: Section 15.207 ----- IC: RSS-Gen 7.2.4	QP 26.9dB, 0.15000MHz, N AV 25.9dB, 0.76775MHz, L	Complied	-
Carrier Frequency Separation	FCC: FCC Public Notice DA 00-705 ----- IC: -	FCC: Section15.247(a)(1) ----- IC: RSS-210 A8.1 (b)	See data.	Complied	Conducted
20dB Bandwidth	FCC: FCC Public Notice DA 00-705 ----- IC: -	FCC: Section15.247(a)(1) ----- IC: RSS-210 A8.1 (a)		Complied	Conducted
Number of Hopping Frequency	FCC: FCC Public Notice DA 00-705 ----- IC: -	FCC: Section15.247(a)(1)(iii) ----- IC: RSS-210 A8.1 (d)		Complied	Conducted
Dwell time	FCC: FCC Public Notice DA 00-705 ----- IC: -	FCC: Section15.247(a)(1)(iii) ----- IC: RSS-210 A8.1 (d)		Complied	Conducted
Maximum Peak Output Power	FCC: FCC Public Notice DA 00-705 ----- IC: RSS-Gen 4.8	FCC: Section15.247(a)(b)(1) ----- IC: RSS-210 A8.4 (2)		Complied	Conducted
Spurious Emission & Band Edge Compliance	FCC: FCC Public Notice DA 00-705 ----- IC: RSS-Gen 4.9	FCC: Section15.247(d) ----- IC: RSS-210 A8.5 RSS-Gen 6 and 7.2.3		6.0 dB 4804.00MHz, AV, Vertical	Complied

Note: UL Japan, Inc.'s EMI Work Procedures No. 13-EM-W0420 and 13-EM-W0422.

\* In case any questions arise about test procedure, ANSI C63.4: 2003 is also referred.

**FCC 15.31 (e)**

This EUT provides stable voltage (DC3.3V) constantly to RF part regardless of input voltage. Therefore, this EUT complies with the requirement.

**FCC Part 15.203 Antenna requirement**

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

**3.3 Addition to standard**

Item	Test Procedure	Specification	Worst margin	Results	Remarks
99% Occupied Bandwidth	IC: RSS-Gen 4.6.1	IC: RSS-Gen 4.6.1	N/A	-	Conducted

Other than above, no addition, exclusion nor deviation has been made from the standard.

**3.4 Uncertainty**

**EMI**

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi-anechoic chamber)	Conducted emission (+dB)
	150kHz-30MHz
No.1	3.5dB
No.2	3.6dB
No.3	3.6dB
No.4	3.6dB

Test room (semi-anechoic chamber)	Radiated emission						
	(3m*)(+dB)				(1m*)(+dB)		(0.5m*)(+dB)
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	1GHz -10GHz	10GHz -18GHz	18GHz -26.5GHz	26.5GHz -40GHz
No.1	4.3dB	5.0dB	5.1dB	4.9dB	5.8dB	4.4dB	4.3dB
No.2	4.3dB	5.2dB	5.1dB	5.0dB	5.7dB	4.3dB	4.2dB
No.3	4.6dB	5.0dB	5.1dB	5.0dB	5.7dB	4.5dB	4.2dB
No.4	4.8dB	5.2dB	5.0dB	5.0dB	5.7dB	5.2dB	4.2dB

\*3m/1m/0.5m = Measurement distance

Power meter (+dB)	
Below 1GHz	Above 1GHz
1.0dB	1.0dB

Antenna terminal conducted emission and Power density (+dB)			Antenna terminal conducted emission (+dB)		Channel power (+dB)
Below 1GHz	1GHz-3GHz	3GHz-18GHz	18GHz-26.5GHz	26.5GHz-40GHz	
1.0dB	1.1dB	2.7dB	3.2dB	3.3dB	1.5dB

Conducted Emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test(3m)

The data listed in this test report has enough margin, more than the site margin.

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### 3.5 Test Location

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	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

\* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

### 3.6 Data of EMI, Test instruments, and Test set up

Refer to APPENDIX.

## **SECTION 4: Operation of E.U.T. during testing**

### **4.1 Operating Mode(s)**

Bluetooth (BT): Transmitting (Tx), Payload: PRBS9  
\*Inquiry mode was not able to function on test tool.

#### Details of Operating Mode(s)

<b>Test Item</b>	<b>Mode</b>	<b>Tested frequency</b>
Conducted Emission, Spurious Emission (Conducted/Radiated)	Tx (Hopping off) DH5, 3DH5	2402MHz 2441MHz 2480MHz
Carrier Frequency Separation	Tx (Hopping on) DH5, 3DH5	2402MHz 2441MHz 2480MHz
20dB Bandwidth	Tx (Hopping off) DH5, 3DH5	2402MHz 2441MHz 2480MHz
Number of Hopping Frequency	Tx (Hopping on) DH5, 3DH5	-
Dwell time	Tx (Hopping on), -DH1, DH3, DH5 -3DH1, 3DH3, 3DH5	-
Maximum Peak Output Power	Tx (Hopping off) DH5, 3DH5	2402MHz 2441MHz 2480MHz
Band Edge Compliance (Conducted)	Tx DH5, 3DH5 -Hopping on -Hopping off	2402MHz 2480MHz
99% Occupied Bandwidth	Tx DH5, 3DH5 -Hopping on -Hopping off	2402MHz 2441MHz 2480MHz
<p>*As a result of preliminary test, the formal test was performed with the above modes, which had the maximum payload length (except Dwell time test)  *EUT has the power settings by the software as follows;  - Power settings: CSR Blue Test 3 Version 2.2.0.0  - Software: Ext 255 Int 50  *This setting of software is the worst case.  Any conditions under the normal use do not exceed the condition of setting.  In addition, end users cannot change the settings of the output power of the product.</p>		

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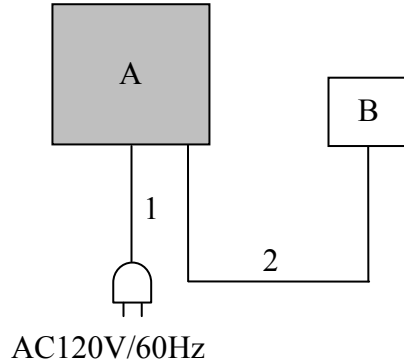
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#### 4.2 Configuration and peripherals



\* Cabling and setup(s) were taken into consideration and test data was taken under worse case conditions.

#### Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remark
A	Wireless Speaker System	SC-NE1	002	Panasonic	EUT
B	iPod nano	MC525J/A	-	Apple	-

#### List of cables used

No.	Name	Length (m)	Shield		Remark
			Cable	Connector	
1	AC Cable	1.6	Unshielded	Unshielded	-
2	Audio Cable	3.0	Shielded	Shielded	

## **SECTION 5: Conducted Emission**

### **Test Procedure and conditions**

EUT was placed on a urethane platform of nominal size, 0.5m by 1.0m, raised 0.8m above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT, including peripherals aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from a Line Impedance Stabilization Network (LISN)/ Artificial mains Network (AMN) and excess AC cable was bundled in center.

#### For the tests on EUT with other peripherals (as a whole system)

I/O cables that were connected to the peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. All unused 50ohm connectors of the LISN(AMN) were resistivity terminated in 50ohm when not connected to the measuring equipment.

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT in a Semi Anechoic Chamber . The EUT was connected to a LISN (AMN).

An overview sweep with peak detection has been performed.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

<b>Detector</b>	<b>: QP and AV</b>
<b>Measurement range</b>	<b>: 0.15-30MHz</b>
<b>Test data</b>	<b>: APPENDIX</b>
<b>Test result</b>	<b>: Pass</b>

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## **SECTION 6: Radiated Spurious Emission**

### **Test Procedure**

EUT was placed on a urethane platform of nominal size, 0.5m by 1.0m, raised 0.8m above the conducting ground plane. The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane.

The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.

The measurements were made with the following detector function of the test receiver and the Spectrum analyzer (in linear mode).

The test was made with the detector (RBW/VBW) in the following table.

When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

### **Test Antennas are used as below;**

Frequency	30MHz to 300MHz	300MHz to 1GHz	Above 1GHz
Antenna Type	Biconical	Logperiodic	Horn

In any 100kHz bandwidth outside the restricted band in which the spread spectrum intentional radiator is operating, the radio frequency power that is produced by the intentional radiator confirmed 20dB below that in the 100kHz bandwidth within the band that contains the highest level of the desired power, based on a radiated measurement.

**20dBc was applied to the frequency over the limit of FCC 15.209 / Table 5 of RSS-Gen 7.2.5 (IC) and outside the restricted band of FCC15.205 / Table 3 of RSS-Gen 7.2.2 (IC).**

Frequency	Below 1GHz	Above 1GHz		20dBc
Instrument used	Test Receiver	Spectrum Analyzer		Spectrum Analyzer
Detector	QP	PK	AV	PK
IF Bandwidth	BW 120kHz(T/R)	RBW: 1MHz VBW: 3MHz	RBW: 1MHz VBW: 10Hz *1)	RBW: 100kHz VBW: 300kHz (S/A)
Test Distance	3m	3m (below 10GHz), 1m*2) (above 10GHz)		3m (below 10GHz), 1m*2) (above 10GHz)

\*1) Although 00-705 accepts VBW=10Hz for AV measurements, it was confirmed that superfluous smoothing was not performed.”

\*2) Distance Factor:  $20 \times \log(3.0\text{m}/1.0\text{m}) = 9.5\text{dB}$

The test was made on EUT at the normal use position.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

**Measurement range : 30M-25GHz**  
**Test data : APPENDIX**  
**Test result : Pass**

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## **SECTION 7: Antenna Terminal Conducted Tests**

### **Test Procedure**

The tests were made with below setting connected to the antenna port.

<b>Test</b>	<b>Span</b>	<b>RBW</b>	<b>VBW</b>	<b>Sweep time</b>	<b>Detector</b>	<b>Trace</b>	<b>Instrument used</b>
20dB Bandwidth	3MHz	30kHz	100kHz	Auto	Peak	Max Hold	Spectrum Analyzer
99% Occupied Bandwidth	Enough width to display 20dB Bandwidth	1 to 3% of Span	Three times of RBW	Auto	Peak	Max Hold	Spectrum Analyzer
Maximum Peak Output Power	-	-	-	Auto	Peak	-	Power Meter (Sensor: 50MHz BW)
Carrier Frequency Separation	3MHz	30kHz	100kHz	Auto	Peak	Max Hold	Spectrum Analyzer
Number of Hopping Frequency	30MHz	300kHz	1MHz	Auto	Peak	Max Hold	Spectrum Analyzer
Dwell Time	Zero Span	100kHz, 1MHz	300kHz, 3MHz	As necessary capture the entire dwell time per hopping channel	Peak	Max Hold	Spectrum Analyzer
Conducted Spurious Emission *1)	9kHz to 150kHz	200Hz	620Hz	Auto	Peak	Max Hold	Spectrum Analyzer
	150kHz to 30MHz	9.1kHz	27kHz				
	30MHz to 25GHz (Less or equal to 5GHz)	100kHz	300kHz				
Conducted Spurious Emission Band Edge compliance	20MHz	100kHz	300kHz	Auto	Peak	Max Hold	Spectrum Analyzer

\*1) In the frequency range below 30MHz, RBW was narrowed to separate the noise contents. Then, wide-band noise near the limit was checked separately, however the noise was not detected as shown in the chart.(9kHz-150kHz:RBW=200Hz, 150kHz-30MHz:RBW=9.1kHz)

The test results and limit are rounded off to two decimals place, so some differences might be observed.

**Test data** : **APPENDIX**  
**Test result** : **Pass**

**APPENDIX 1: Data of EMI test**

**Conducted Emission**

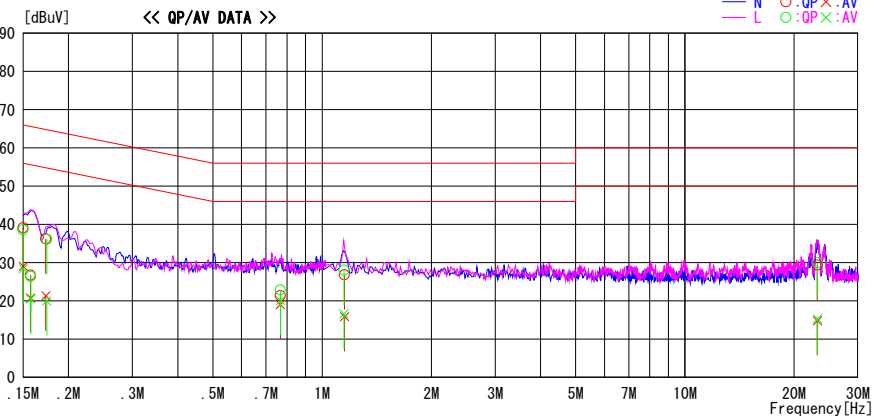
**DATA OF CONDUCTED EMISSION TEST**

UL Japan, Inc. Head Office EMC Lab. No. 4 Semi Anechoic Chamber  
 Date : 2012/11/27

Report No. : 33BE0184-HO-04  
 Temp./Humi. : 21deg. C / 35% RH  
 Engineer : Hironobu Ohnishi

Mode / Remarks : Tx DH5 2402MHz

LIMIT : FCC15.207 QP  
 FCC15.207 AV

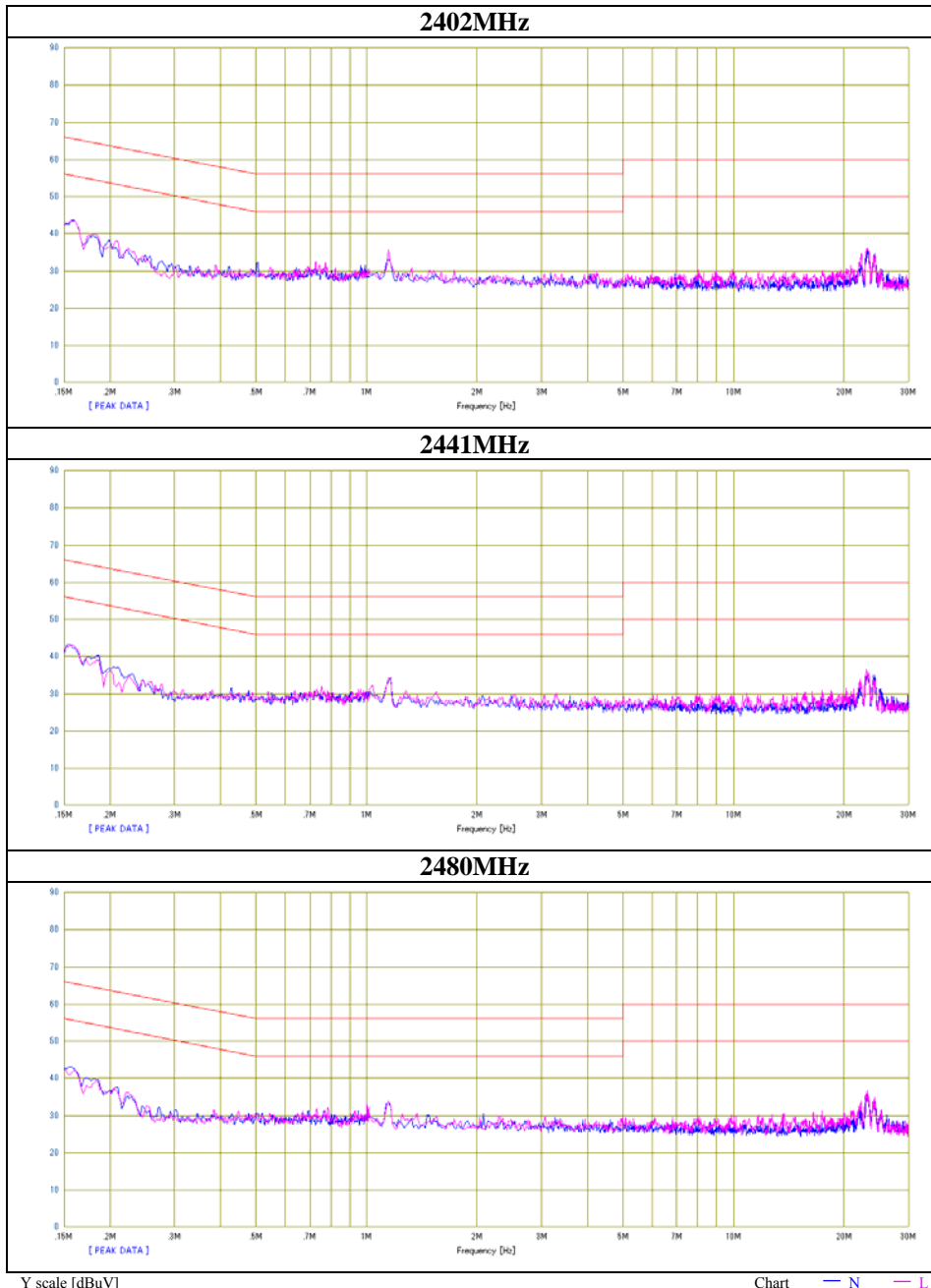


Frequency [MHz]	Reading Level		Corr. Factor	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.15000	25.8	15.8	13.3	39.1	29.1	66.0	56.0	26.9	26.9	N	
0.15721	13.4	7.5	13.3	26.7	20.8	65.6	55.6	38.9	34.8	N	
0.17324	22.9	8.0	13.3	36.2	21.3	64.8	54.8	28.6	33.5	N	
0.76721	8.0	5.7	13.4	21.4	19.1	56.0	46.0	34.6	26.9	N	
1.15218	13.4	2.5	13.4	26.8	15.9	56.0	46.0	29.2	30.1	N	
23.17753	14.6	0.0	14.8	29.4	14.8	60.0	50.0	30.6	35.2	N	
0.15000	25.3	15.1	13.3	38.6	28.4	66.0	56.0	27.4	27.6	L	
0.15725	13.1	7.2	13.3	26.4	20.5	65.6	55.6	39.2	35.1	L	
0.17410	22.8	6.7	13.3	36.1	20.0	64.8	54.8	28.7	34.8	L	
0.76775	9.4	6.7	13.4	22.8	20.1	56.0	46.0	33.2	25.9	L	
1.14869	14.6	3.2	13.4	28.0	16.6	56.0	46.0	28.0	29.4	L	
23.17841	15.2	0.5	14.8	30.0	15.3	60.0	50.0	30.0	34.7	L	

CHART: WITH FACTOR, Peak hold data. CALCULATION: RESULT=READING+C. F (LISN LOSS+ATT LOSS +CABLE LOSS)  
 Except for the above table : adequate margin data below the limits.

## Conducted Emission

Test place	Head Office EMC Lab. No.4 Semi Anechoic Chamber
Report No.	33BE0184-HO-04
Date	11/27/2012
Temperature/ Humidity	21 deg. C / 35% RH
Engineer	Hironobu Ohnishi
Mode	Tx DH5



## Conducted Emission

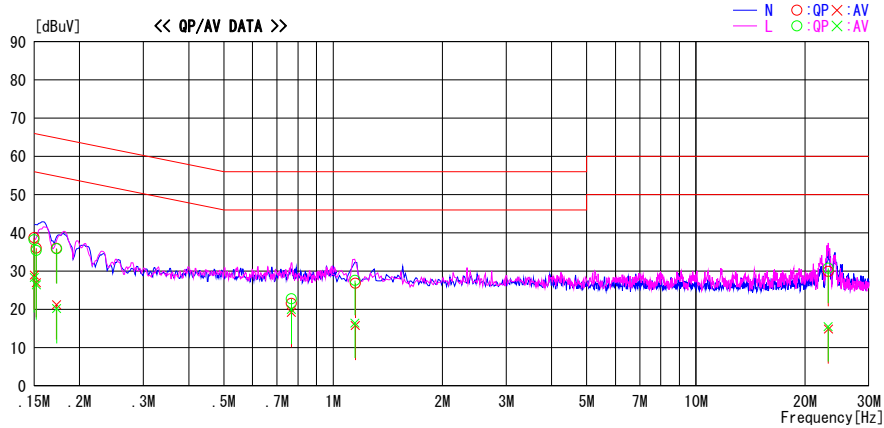
### DATA OF CONDUCTED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No. 4 Semi Anechoic Chamber  
 Date : 2012/11/27

Report No. : 33BE0184-HO-04  
 Temp./Humi. : 21deg. C / 35% RH  
 Engineer : Hironobu Ohnishi

Mode / Remarks : Tx 3DH5 2402MHz

LIMIT : FCC15.207 QP  
 FCC15.207 AV

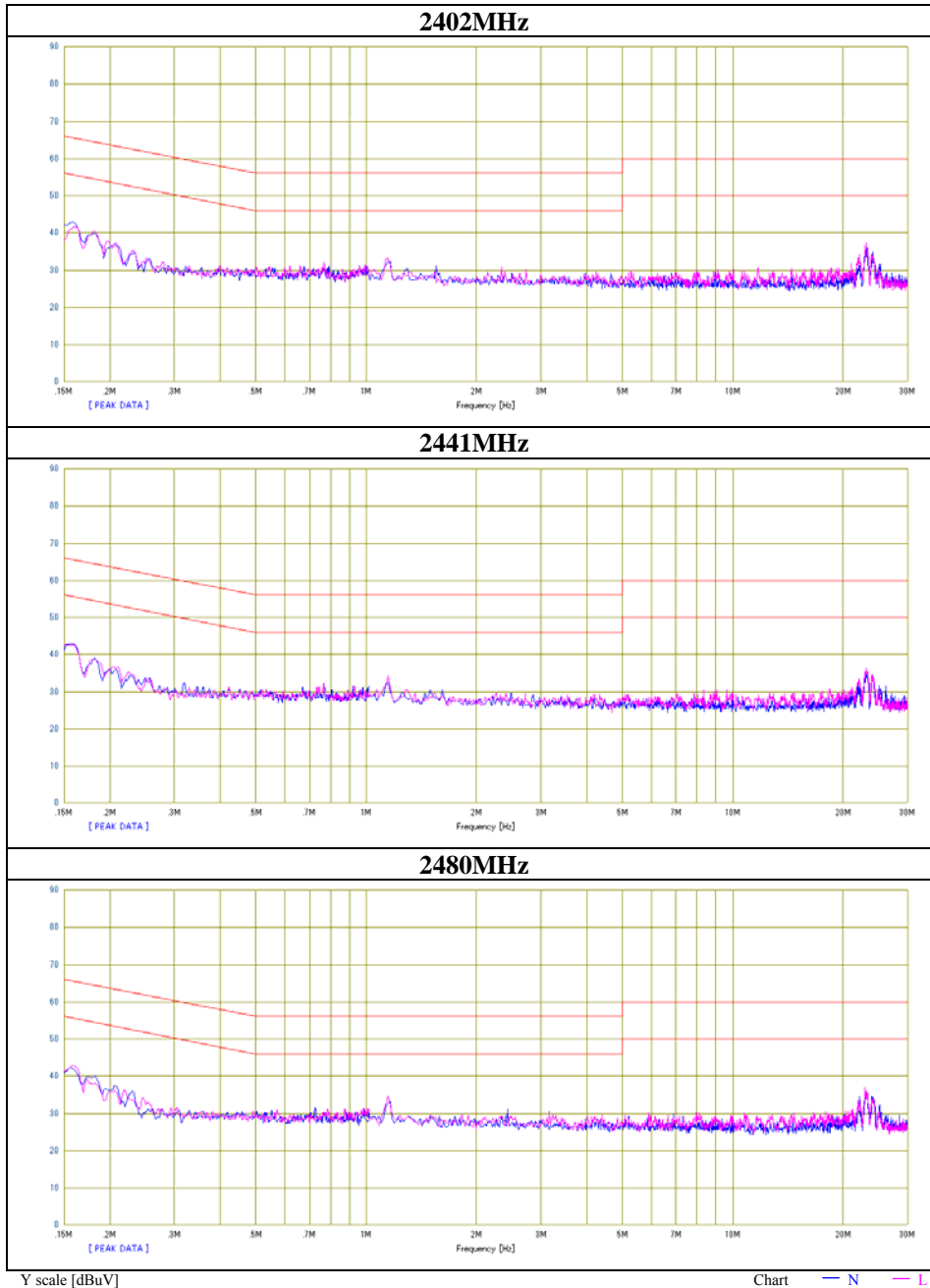


Frequency [MHz]	Reading Level		Corr. Factor	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.15000	25.4	15.7	13.3	38.7	29.0	66.0	56.0	27.3	27.0	N	
0.15208	22.7	13.7	13.3	36.0	27.0	65.9	55.9	29.9	28.9	N	
0.17285	22.6	7.9	13.3	35.9	21.2	64.8	54.8	28.9	33.6	N	
0.76754	8.2	5.8	13.4	21.6	19.2	56.0	46.0	34.4	26.8	N	
1.15126	13.4	2.4	13.4	26.8	15.8	56.0	46.0	29.2	30.2	N	
23.16800	15.1	0.1	14.8	29.9	14.9	60.0	50.0	30.1	35.1	N	
0.15000	24.9	15.0	13.3	38.2	28.3	66.0	56.0	27.8	27.7	L	
0.15210	22.1	13.1	13.3	35.4	26.4	65.9	55.9	30.5	29.5	L	
0.17298	22.5	6.9	13.3	35.8	20.2	64.8	54.8	29.0	34.6	L	
0.76725	9.3	6.6	13.4	22.7	20.0	56.0	46.0	33.3	26.0	L	
1.14865	14.2	3.0	13.4	27.6	16.4	56.0	46.0	28.4	29.6	L	
23.15000	15.9	0.7	14.8	30.7	15.5	60.0	50.0	29.3	34.5	L	

CHART: WITH FACTOR, Peak hold data. CALCULATION: RESULT=READING+C.F (LISN LOSS+ATT LOSS +CABLE LOSS)  
 Except for the above table : adequate margin data below the limits.

## Conducted Emission

Test place	Head Office EMC Lab. No.4 Semi Anechoic Chamber
Report No.	33BE0184-HO-04
Date	11/27/2012
Temperature/ Humidity	21 deg. C / 35% RH
Engineer	Hironobu Ohnishi
Mode	Tx 3DH5



## 20dB Bandwidth and Carrier Frequency Separation

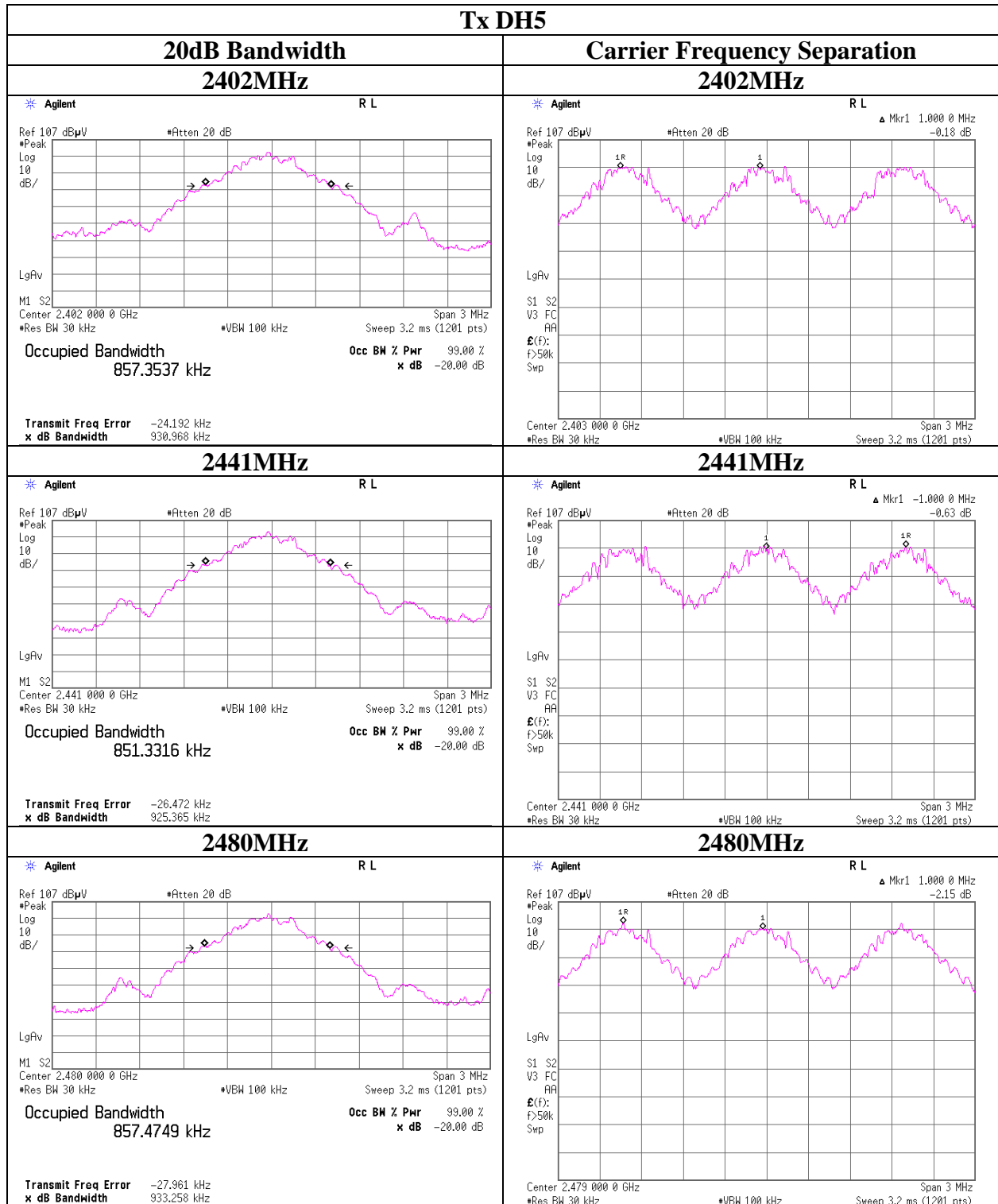
Test place Head Office EMC Lab. No.6 Shielded Room  
Report No. 33BE0184-HO-04  
Date 10/16/2012  
Temperature/ Humidity 25 deg. C / 43% RH  
Engineer Tomohisa Nakagawa  
Mode Tx (Hopping on) DH5/3DH5

Mode	Freq. [MHz]	20dB Bandwidth [MHz]	Carrier Frequency Separation [MHz]	Limit for Carrier Frequency separation [MHz]
DH5	2402.0	0.931	1.000	$\geq 0.621$
DH5	2441.0	0.925	1.000	$\geq 0.617$
DH5	2480.0	0.933	1.000	$\geq 0.622$
3DH5	2402.0	1.285	1.000	$\geq 0.857$
3DH5	2441.0	1.301	1.000	$\geq 0.867$
3DH5	2480.0	1.280	1.000	$\geq 0.853$

Limit: Two-thirds of 20dB Bandwidth or 25kHz (whichever is greater).

No limit applies to 20dB Bandwidth.

**20dB Bandwidth and Carrier Frequency Separation**





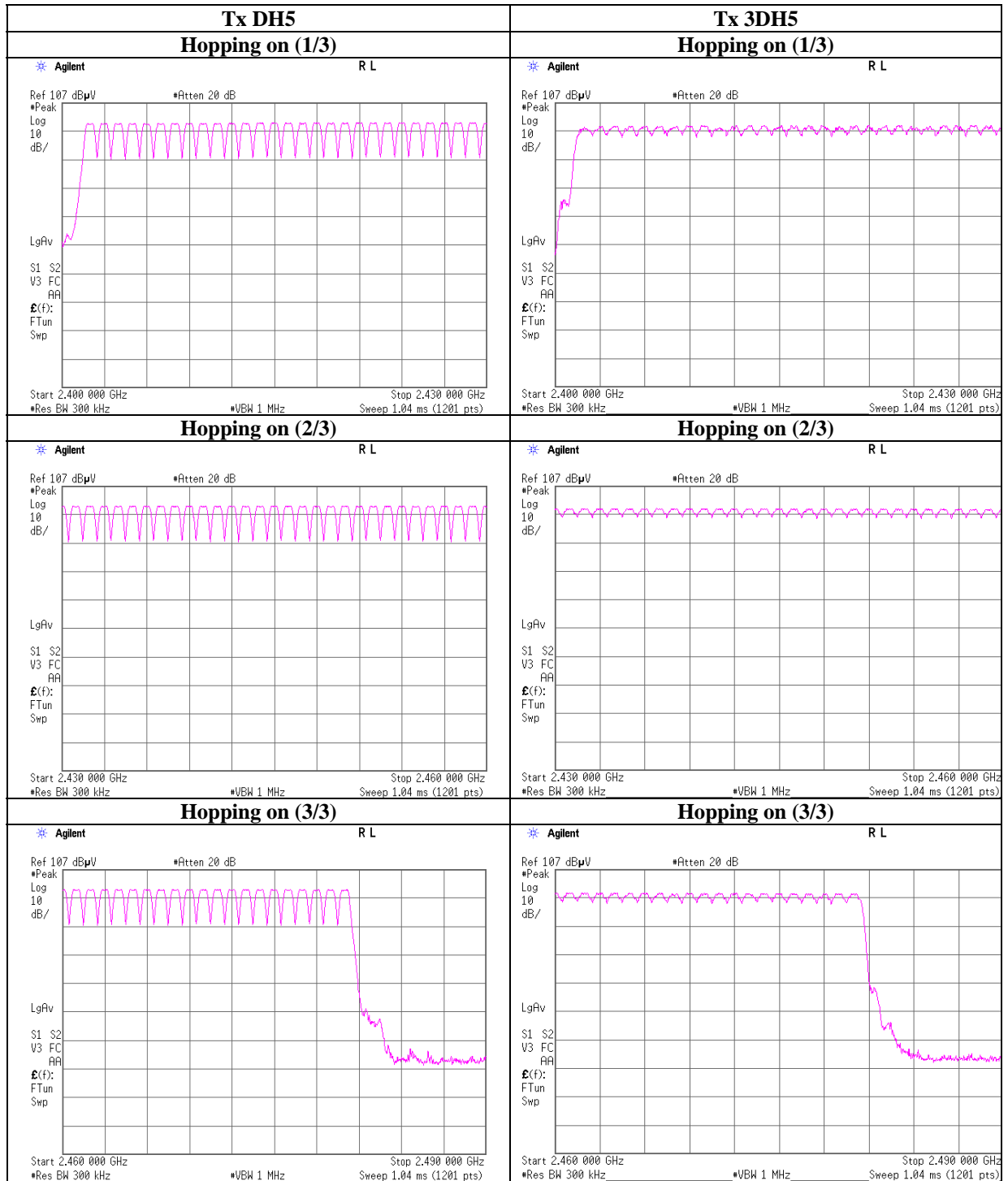
### Number of Hopping Frequency

Test place Head Office EMC Lab. No.6 Shielded Room  
Report No. 33BE0184-HO-04  
Date 10/16/2012  
Temperature/ Humidity 25 deg. C / 43% RH  
Engineer Tomohisa Nakagawa  
Mode Tx (Hopping on) DH5/3DH5

Mode	Number of channel [times]	Limit [times]
DH5	79	$\geq 15$
3DH5	79	$\geq 15$

Test was not performed at AFH mode whose number of hopping channel is 20 channels because this Bluetooth radio is in compliance of Bluetooth Specification.

### Number of Hopping Frequency



### Dwell time

Test place Head Office EMC Lab. No.6 Shielded Room  
 Report No. 33BE0184-HO-04  
 Date 10/16/2012  
 Temperature/ Humidity 25 deg. C / 43% RH  
 Engineer Tomohisa Nakagawa  
 Mode Tx (Hopping on) DH5/3DH5

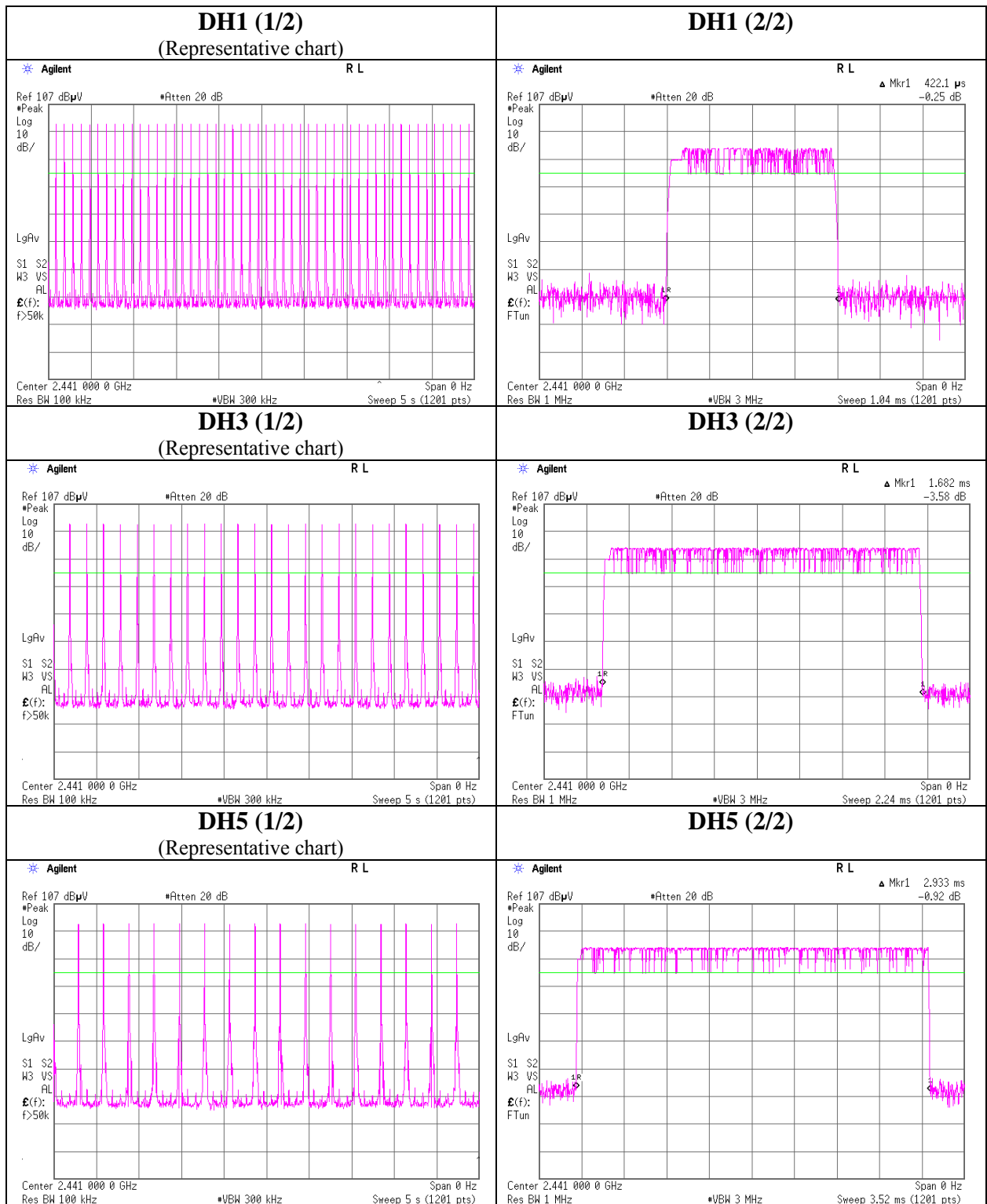
Mode	Number of transmission in a 31.6(79 Hopping x 0.4) / 12.8(32 Hopping x 0.4)second period				Length of transmission time [msec]	Result [msec]	Limit [msec]
DH1	50.0 times /	5 sec. x	31.6 sec. =	316 times	0.422	133	400
DH3	25.0 times /	5 sec. x	31.6 sec. =	158 times	1.682	266	400
DH5	16.0 times /	5 sec. x	31.6 sec. =	102 times	2.933	299	400
3DH1	50.0 times /	5 sec. x	31.6 sec. =	316 times	0.435	137	400
3DH3	25.0 times /	5 sec. x	31.6 sec. =	158 times	1.689	267	400
3DH5	16.0 times /	5 sec. x	31.6 sec. =	102 times	2.939	300	400

Sample Calculation

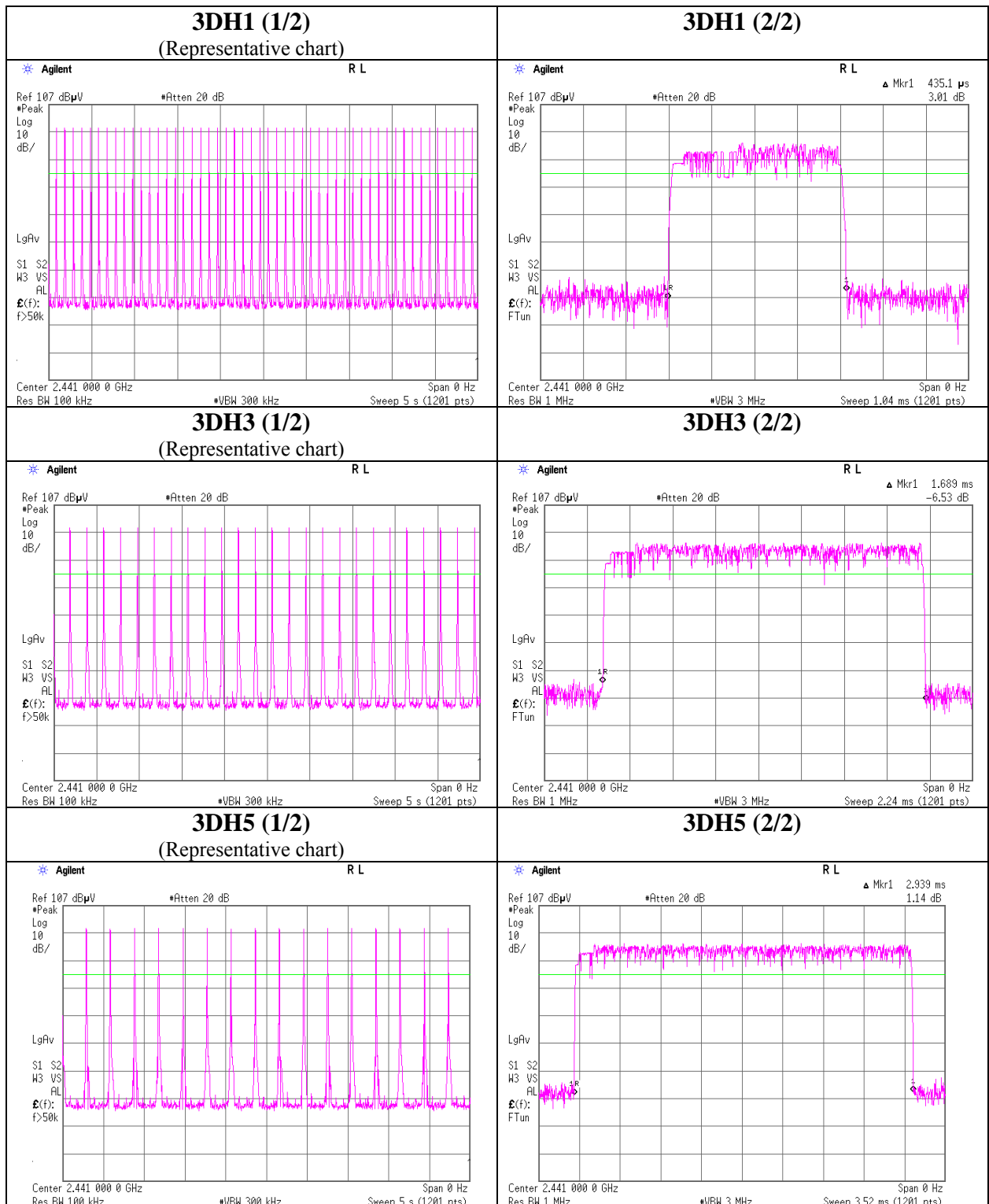
Result = Number of transmission x Length of transmission time

This device complies with the Bluetooth protocol for FHSS operation, employing a pseudo random channel selection and hopping rate to ensure that the occupancy time in  $N \times 0.4s$ , where  $N$  is the number of channels being used in the hopping sequence ( $20 \leq N \leq 79$ ), is always less than  $0.4s$  regardless of packet size. This is confirmed in the test report for  $N=79$ .

**Dwell time**



**Dwell time**



### Maximum Peak Output Power

Test place                      Head Office EMC Lab. No.6 Shielded Room  
Report No.                      33BE0184-HO-04  
Date                              10/16/2012  
Temperature/ Humidity        25 deg. C / 43% RH  
Engineer                        Tomohisa Nakagawa  
Mode                              Tx (Hopping off) DH5/3DH5

Mode	Freq. [MHz]	Reading [dBm]	Cable Loss [dB]	Atten. [dB]	Result		Limit		Margin [dB]
					[dBm]	[mW]	[dBm]	[mW]	
DH5	2402.0	-8.21	0.77	10.03	2.59	1.82	20.96	125	18.37
DH5	2441.0	-8.04	0.77	10.03	2.76	1.89	20.96	125	18.20
DH5	2480.0	-8.21	0.78	10.03	2.60	1.82	20.96	125	18.36
3DH5	2402.0	-10.28	0.77	10.03	0.52	1.13	20.96	125	20.44
3DH5	2441.0	-10.15	0.77	10.03	0.65	1.16	20.96	125	20.31
3DH5	2480.0	-10.19	0.78	10.03	0.62	1.15	20.96	125	20.34

Sample Calculation:

Result = Reading + Cable Loss + Attenuator

Test was not performed at AFH mode, because the decrease of number of channel (min: 20ch) at AFH mode does not influence on the output power and bandwidth of the EUT.

As this device had AFH mode and frequency separation could not meet the requirement of over 20dB BW without 2/3 relaxation, 125mW power limit was applied to it.

## Radiated Spurious Emission

Test place Head Office EMC Lab. No.4 Semi Anechoic Chamber  
Report No. 33BE0184-HO-04  
Date 11/26/2012 11/26/2012 11/28/2012  
Temperature/ Humidity 21 deg. C / 35% RH 21 deg. C / 35% RH 22 deg. C / 41% RH  
Engineer Tomohisa Nakagawa Hironobu Ohnishi Tomotaka Sasagawa  
(1-10GHz) (Above 10GHz) (Below 1GHz)  
Mode Tx, DH5 2402MHz

Polarity	Frequency [MHz]	Detector	Reading [dBuV]	Ant.Fac. [dB/m]	Loss [dB]	Gain [dB]	Result [dBuV/m]	Limit [dBuV/m]	Margin [dB]	Remark
Hori	40.822	QP	24.5	14.5	7.3	32.0	14.3	40.0	25.7	
Hori	73.828	QP	33.8	6.6	7.7	32.1	16.0	40.0	24.0	
Hori	110.621	QP	38.0	11.7	8.2	32.0	25.9	43.5	17.6	
Hori	135.511	QP	33.3	14.2	8.5	32.0	24.0	43.5	19.5	
Hori	159.860	QP	31.6	15.4	8.6	32.0	23.6	43.5	19.9	
Hori	295.670	QP	30.7	19.9	9.6	32.0	28.2	46.0	17.8	
Hori	2390.000	PK	47.5	27.5	2.4	32.3	45.1	73.9	28.8	
Hori	4804.000	PK	52.4	31.3	4.9	31.5	57.1	73.9	16.8	
Hori	7206.000	PK	43.5	35.8	5.9	32.5	52.7	73.9	21.2	
Hori	9608.000	PK	42.1	38.3	6.8	32.9	54.3	73.9	19.6	
Hori	2390.000	AV	30.4	27.5	2.4	32.3	28.0	53.9	25.9	
Hori	7206.000	AV	30.5	35.8	5.9	32.5	39.7	53.9	14.2	
Hori	9608.000	AV	31.7	38.3	6.8	32.9	43.9	53.9	10.0	
Vert	39.198	QP	39.6	15.1	7.2	32.0	29.9	40.0	10.1	
Vert	73.828	QP	47.4	6.6	7.7	32.1	29.6	40.0	10.4	
Vert	110.080	QP	34.5	11.6	8.2	32.0	22.3	43.5	21.2	
Vert	135.511	QP	37.2	14.2	8.5	32.0	27.9	43.5	15.6	
Vert	159.860	QP	34.5	15.4	8.6	32.0	26.5	43.5	17.0	
Vert	295.670	QP	32.4	19.9	9.6	32.0	29.9	46.0	16.1	
Vert	2390.000	PK	42.5	27.5	2.4	32.3	40.1	73.9	33.8	
Vert	4804.000	PK	55.3	31.3	4.9	31.5	60.0	73.9	13.9	
Vert	7206.000	PK	42.1	35.8	5.9	32.5	51.3	73.9	22.6	
Vert	9608.000	PK	41.7	38.3	6.8	32.9	53.9	73.9	20.0	
Vert	2390.000	AV	31.5	27.5	2.4	32.3	29.1	53.9	24.8	
Vert	7206.000	AV	31.7	35.8	5.9	32.5	40.9	53.9	13.0	
Vert	9608.000	AV	31.2	38.3	6.8	32.9	43.4	53.9	10.5	

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter-Distance factor(above 10GHz)) - Gain(Amplifier)

\*Other frequency noises omitted in this report were not seen or had enough margin (more than 20dB).

\*The 10th harmonic was not seen so the result was its base noise level.

Distance factor: 10GHz-26.5GHz 20log(3.0m/1.0m)= 9.5dB  
26.5GHz-40GHz 20log(3.0m/0.5m)=15.6dB

## Radiated Spurious Emission

Test place : Head Office EMC Lab. No.4 Semi Anechoic Chamber  
Report No. : 33BE0184-HO-04  
Date : 11/26/2012  
Temperature/ Humidity : 21 deg. C / 35% RH  
Engineer : Tomohisa Nakagawa  
(1-10GHz)  
Mode : Tx, DH5 2402MHz

### 20dBc Data Sheet

Polarity	Frequency [MHz]	Detector	Reading [dBuV]	Ant Factor [dB/m]	Loss [dB]	Gain [dB]	Result dBuV/m	Limit dBuV/m	Margin [dB]	Remark
Hori	2402.000	PK	96.5	27.5	2.4	32.3	94.1	-	-	Carrier
Hori	2400.000	PK	57.3	27.5	2.4	32.3	54.9	74.1	19.2	
Hori	2399.500	PK	54.4	27.5	2.4	32.3	52.0	74.1	22.1	
Vert	2402.000	PK	102.3	27.5	2.4	32.3	99.9	-	-	Carrier
Vert	2400.000	PK	62.6	27.5	2.4	32.3	60.2	79.9	19.7	
Vert	2399.500	PK	59.3	27.5	2.4	32.3	56.9	79.9	23.0	

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter-Distance factor(above 10GHz)) - Gain(Amplifier)

### Dwell time factor relaxation

Polarity	Frequency [MHz]	Detector	Reading [dBuV]	Ant Factor [dB/m]	Loss [dB]	Gain [dB]	Dwell Factor [dB]	Result dBuV/m	Limit dBuV/m	Margin [dB]	Remark
Hori	4804.000	AV	47.1	31.3	4.9	31.5	-24.6	27.2	53.9	26.7	
Vert	4804.000	AV	51.4	31.3	4.9	31.5	-24.6	31.5	53.9	22.4	

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter-Distance factor(above 10GHz))

- Gain(Amplifier) + Dwell time factor (Refer to dwell time data sheet)

\*Other frequency noises omitted in this report were not seen or had enough margin (more than 20dB).

Distance factor:      10GHz-26.5GHz    20log(3.0m/1.0m)= 9.5dB  
                             26.5GHz-40GHz    20log(3.0m/0.5m)=15.6dB

## Radiated Spurious Emission

Test place Head Office EMC Lab. No.4 Semi Anechoic Chamber  
Report No. 33BE0184-HO-04  
Date 11/26/2012 11/26/2012 11/28/2012  
Temperature/ Humidity 21 deg. C / 35% RH 21 deg. C / 35% RH 22 deg. C / 41% RH  
Engineer Tomohisa Nakagawa Hironobu Ohnishi Tomotaka Sasagawa  
(1-10GHz) (Above 10GHz) (Below 1GHz)  
Mode Tx, DH5 2441MHz

Polarity	Frequency [MHz]	Detector	Reading [dBuV]	Ant.Fac. [dB/m]	Loss [dB]	Gain [dB]	Result [dBuV/m]	Limit [dBuV/m]	Margin [dB]	Remark
Hori	40.521	QP	24.3	14.6	7.3	32.0	14.2	40.0	25.8	
Hori	73.841	QP	33.9	6.6	7.8	32.1	16.2	40.0	23.8	
Hori	110.421	QP	38.0	11.7	8.2	32.0	25.9	43.5	17.6	
Hori	135.653	QP	33.5	14.3	8.5	32.0	24.3	43.5	19.2	
Hori	159.410	QP	31.7	15.4	8.6	32.0	23.7	43.5	19.8	
Hori	295.621	QP	30.9	19.9	9.6	32.0	28.4	46.0	17.6	
Hori	4882.000	PK	50.4	31.5	5.0	31.5	55.4	73.9	18.6	
Hori	7323.000	PK	42.3	35.8	5.9	32.5	51.5	73.9	22.4	
Hori	9764.000	PK	42.5	38.4	7.1	32.9	55.1	73.9	18.8	
Hori	7323.000	AV	30.2	35.8	5.9	32.5	39.4	53.9	14.5	
Hori	9764.000	AV	30.0	38.4	7.1	32.9	42.6	53.9	11.3	
Vert	38.932	QP	38.0	15.2	7.2	32.0	28.4	40.0	11.6	
Vert	73.521	QP	47.3	6.6	7.7	32.1	29.5	40.0	10.5	
Vert	110.842	QP	34.5	11.7	8.2	32.0	22.4	43.5	21.1	
Vert	135.445	QP	37.5	14.2	8.5	32.0	28.2	43.5	15.3	
Vert	159.421	QP	34.9	15.4	8.6	32.0	26.9	43.5	16.6	
Vert	296.324	QP	32.9	20.0	9.6	32.0	30.5	46.0	15.5	
Vert	4882.000	PK	54.6	31.5	5.0	31.5	59.6	73.9	14.3	
Vert	7323.000	PK	41.4	35.8	5.9	32.5	50.6	73.9	23.3	
Vert	9764.000	PK	42.5	38.4	7.1	32.9	55.1	73.9	18.8	
Vert	7323.000	AV	30.2	35.8	5.9	32.5	39.4	53.9	14.5	
Vert	9764.000	AV	30.1	38.4	7.1	32.9	42.7	53.9	11.3	

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter-Distance factor(above 10GHz)) - Gain(Amplifier)

\*Other frequency noises omitted in this report were not seen or had enough margin (more than 20dB).

\*The 10th harmonic was not seen so the result was its base noise level.

Distance factor: 10GHz-26.5GHz 20log(3.0m/1.0m)= 9.5dB  
26.5GHz-40GHz 20log(3.0m/0.5m)=15.6dB

## Radiated Spurious Emission

Test place : Head Office EMC Lab. No.4 Semi Anechoic Chamber  
 Report No. : 33BE0184-HO-04  
 Date : 11/26/2012  
 Temperature/ Humidity : 21 deg. C / 35% RH  
 Engineer : Tomohisa Nakagawa  
 (1-10GHz)  
 Mode : Tx, DH5 2441MHz

### Dwell time factor relaxation

Polarity	Frequency [MHz]	Detector	Reading [dBuV]	Ant Factor [dB/m]	Loss [dB]	Gain [dB]	Dwell Factor [dB]	Result [dBuV/m]	Limit [dBuV/m]	Margin [dB]	Remark
Hori	4882.000	AV	44.4	31.5	5.0	31.5	-24.6	24.8	53.9	29.1	
Vert	4882.000	AV	49.7	31.5	5.0	31.5	-24.6	30.1	53.9	23.8	

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter-Distance factor(above 10GHz))

- Gain(Amplifier) + Dwell time factor (Refer to dwell time data sheet)

\*Other frequency noises omitted in this report were not seen or had enough margin (more than 20dB).

Distance factor:    10GHz-26.5GHz    20log(3.0m/1.0m)= 9.5dB  
                           26.5GHz-40GHz    20log(3.0m/0.5m)=15.6dB

## Radiated Spurious Emission

Test place Head Office EMC Lab. No.4 Semi Anechoic Chamber  
Report No. 33BE0184-HO-04  
Date 11/26/2012 11/26/2012 11/28/2012  
Temperature/ Humidity 21 deg. C / 35% RH 21 deg. C / 35% RH 22 deg. C / 41% RH  
Engineer Tomohisa Nakagawa Hironobu Ohnishi Tomotaka Sasagawa  
(1-10GHz) (Above 10GHz) (Below 1GHz)  
Mode Tx, DH5 2480MHz

Polarity	Frequency [MHz]	Detector	Reading [dBuV]	Ant.Fac. [dB/m]	Loss [dB]	Gain [dB]	Result [dBuV/m]	Limit [dBuV/m]	Margin [dB]	Remark
Hori	40.521	QP	24.9	14.6	7.3	32.0	14.8	40.0	25.2	
Hori	73.521	QP	34.1	6.6	7.7	32.1	16.3	40.0	23.7	
Hori	110.421	QP	38.2	11.7	8.2	32.0	26.1	43.5	17.4	
Hori	135.242	QP	33.9	14.2	8.5	32.0	24.6	43.5	18.9	
Hori	159.582	QP	32.1	15.4	8.6	32.0	24.1	43.5	19.4	
Hori	295.412	QP	31.2	19.9	9.6	32.0	28.7	46.0	17.3	
Hori	2483.500	PK	47.6	27.5	2.4	32.2	45.3	73.9	28.6	
Hori	4960.000	PK	47.5	31.8	5.0	31.5	52.8	73.9	21.1	
Hori	7440.000	PK	42.6	35.9	6.0	32.6	51.9	73.9	22.0	
Hori	9920.000	PK	42.4	38.6	7.1	33.0	55.1	73.9	18.8	
Hori	2483.500	AV	37.5	27.5	2.4	32.2	35.2	53.9	18.7	
Hori	7440.000	AV	31.3	35.9	6.0	32.6	40.6	53.9	13.3	
Hori	9920.000	AV	30.4	38.6	7.1	33.0	43.1	53.9	10.8	
Vert	40.040	QP	40.0	14.8	7.3	32.0	30.1	40.0	9.9	
Vert	73.542	QP	47.8	6.6	7.7	32.1	30.0	40.0	10.0	
Vert	110.452	QP	34.9	11.7	8.2	32.0	22.8	43.5	20.7	
Vert	135.421	QP	37.4	14.2	8.5	32.0	28.1	43.5	15.4	
Vert	159.782	QP	34.6	15.4	8.6	32.0	26.6	43.5	16.9	
Vert	295.252	QP	32.5	19.9	9.6	32.0	30.0	46.0	16.0	
Vert	2483.500	PK	51.0	27.5	2.4	32.2	48.7	73.9	25.2	
Vert	4960.000	PK	49.8	31.8	5.0	31.5	55.1	73.9	18.8	
Vert	7440.000	PK	43.5	35.9	6.0	32.6	52.8	73.9	21.1	
Vert	9920.000	PK	42.0	38.6	7.1	33.0	54.7	73.9	19.2	
Vert	2483.500	AV	38.6	27.5	2.4	32.2	36.3	53.9	17.6	
Vert	7440.000	AV	31.8	35.9	6.0	32.6	41.1	53.9	12.8	
Vert	9920.000	AV	30.3	38.6	7.1	33.0	43.0	53.9	10.9	

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter-Distance factor(above 10GHz)) - Gain(Amplifier)

\*Other frequency noises omitted in this report were not seen or had enough margin (more than 20dB).

\*The 10th harmonic was not seen so the result was its base noise level.

Distance factor: 10GHz-26.5GHz 20log(3.0m/1.0m)= 9.5dB  
26.5GHz-40GHz 20log(3.0m/0.5m)=15.6dB

## Radiated Spurious Emission

Test place : Head Office EMC Lab. No.4 Semi Anechoic Chamber  
Report No. : 33BE0184-HO-04  
Date : 11/26/2012  
Temperature/ Humidity : 21 deg. C / 35% RH  
Engineer : Tomohisa Nakagawa  
(1-10GHz)  
Mode : Tx, DH5 2480MHz

**Dwell time factor relaxation**

Polarity	Frequency [MHz]	Detector	Reading [dBuV]	Ant Factor [dB/m]	Loss [dB]	Gain [dB]	Dwell Factor [dB]	Result [dBuV/m]	Limit [dBuV/m]	Margin [dB]	Remark
Hori	4960.000	AV	40.2	31.8	5.0	31.5	-24.6	20.9	53.9	33.0	
Vert	4960.000	AV	44.3	31.8	5.0	31.5	-24.6	25.0	53.9	28.9	

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter-Distance factor(above 10GHz))  
- Gain(Amplifier) + Dwell time factor (Refer to dwell time data sheet)

\*Other frequency noises omitted in this report were not seen or had enough margin (more than 20dB).

Distance factor:      10GHz-26.5GHz    20log(3.0m/1.0m)= 9.5dB  
                             26.5GHz-40GHz    20log(3.0m/0.5m)=15.6dB



## Radiated Spurious Emission

Test place : Head Office EMC Lab. No.4 Semi Anechoic Chamber  
 Report No. : 33BE0184-HO-04  
 Date : 11/26/2012  
 Temperature/ Humidity : 21 deg. C / 35% RH  
 Engineer : Tomohisa Nakagawa  
 (1-10GHz)  
 Mode : Tx, 3DH5 2402MHz

**20dBc Data Sheet**

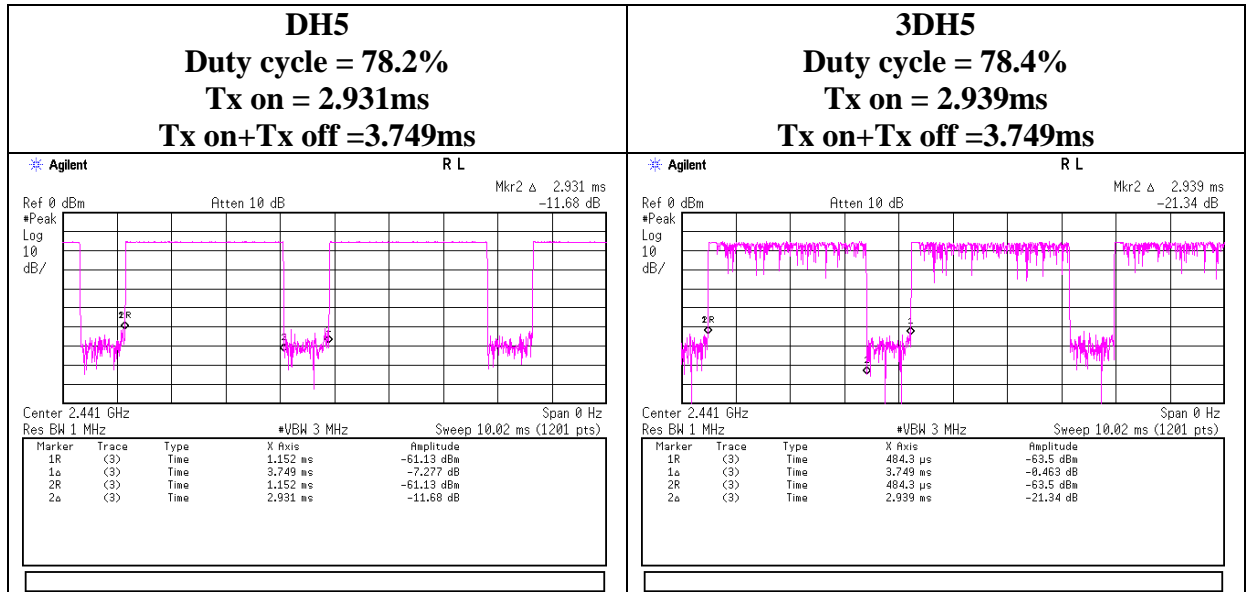
Polarity	Frequency [MHz]	Detector	Reading [dBuV]	Ant Factor [dB/m]	Loss [dB]	Gain [dB]	Result [dBuV/m]	Limit [dBuV/m]	Margin [dB]	Remark
Hori	2402.000	PK	96.6	27.5	2.4	32.3	94.2	-	-	Carrier
Hori	2399.500	PK	52.6	27.5	2.4	32.3	50.2	74.2	24.0	
Hori	2400.000	PK	54.6	27.5	2.4	32.3	52.2	74.2	22.0	
Vert	2402.000	PK	101.1	27.5	2.4	32.3	98.7	-	-	Carrier
Vert	2399.500	PK	56.5	27.5	2.4	32.3	54.1	78.7	24.6	
Vert	2400.000	PK	58.7	27.5	2.4	32.3	56.3	78.7	22.4	

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter-Distance factor(above 10GHz)) - Gain(Amplifier)



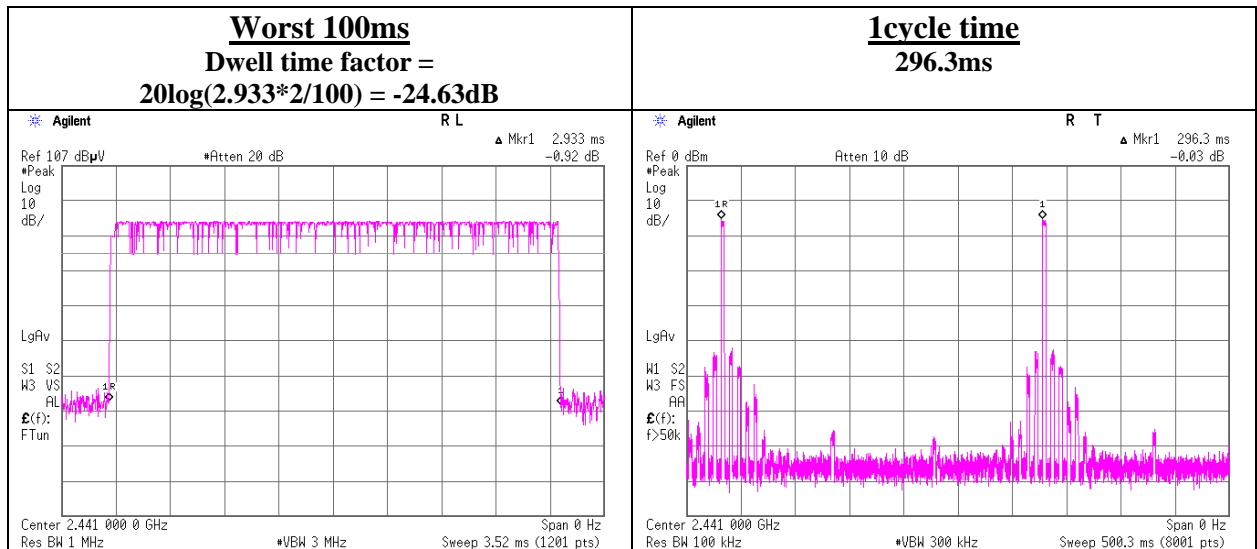


**Burst rate confirmation**



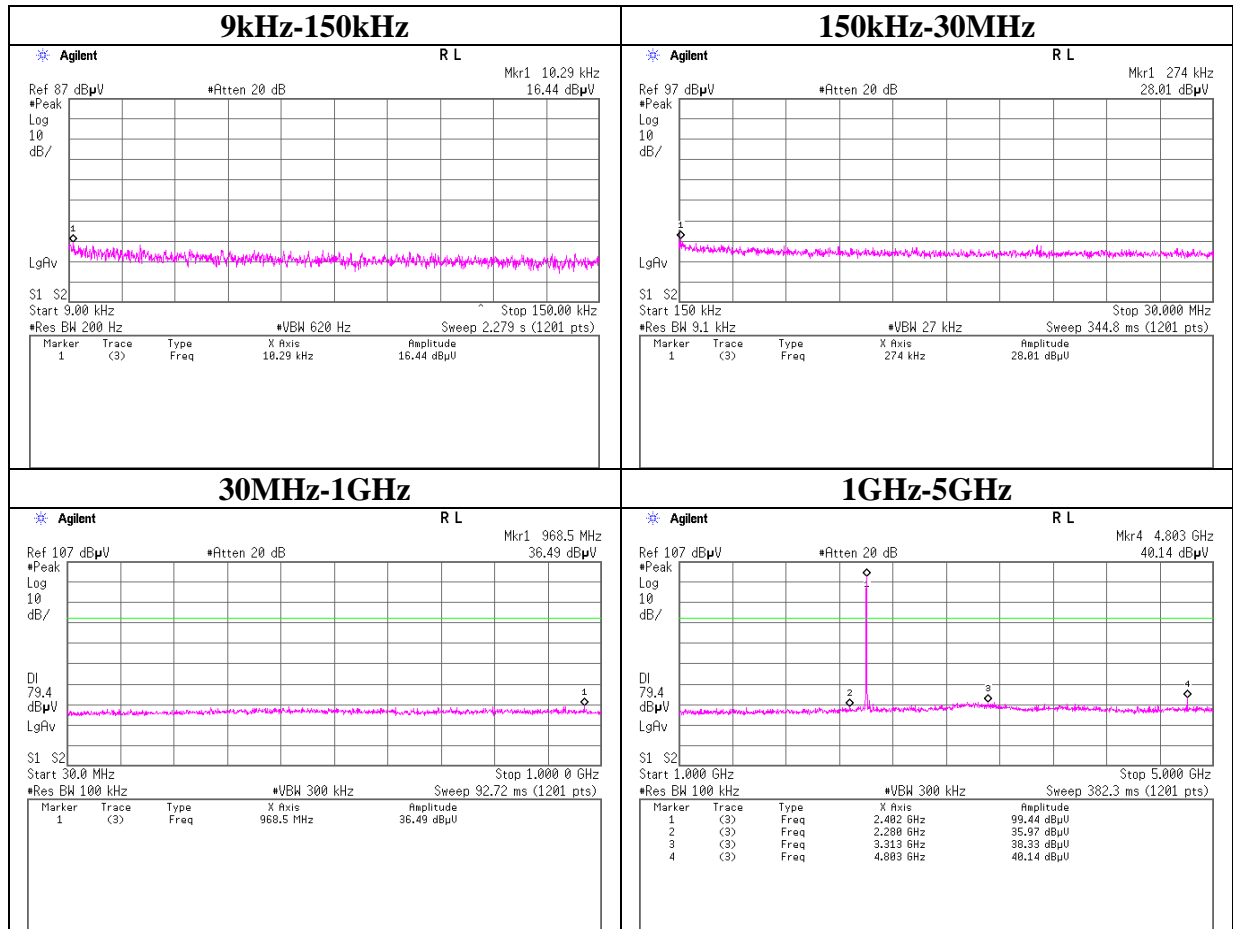
**Dwell time factor**

**DH5**



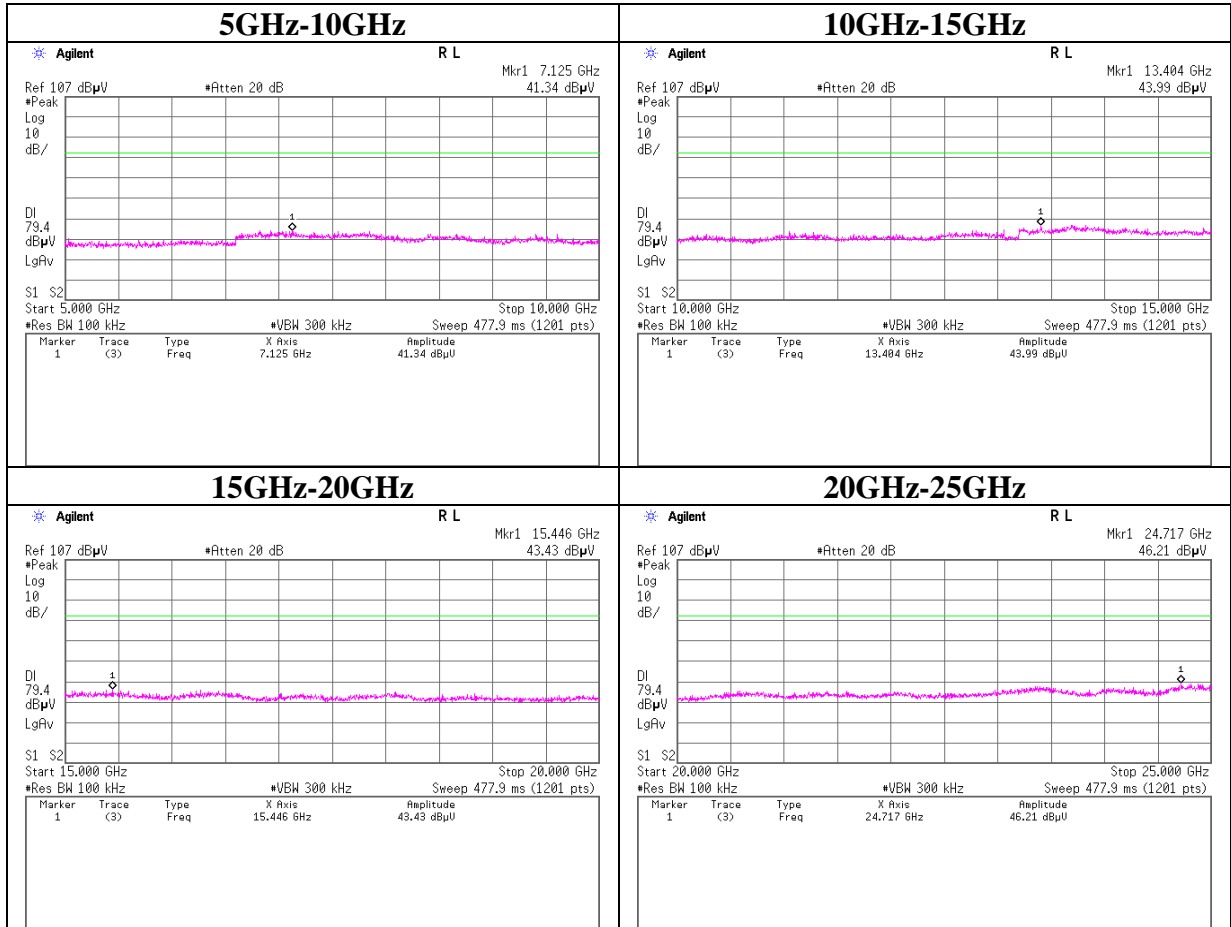
## Conducted Spurious Emission

### Tx DH5 2402MHz



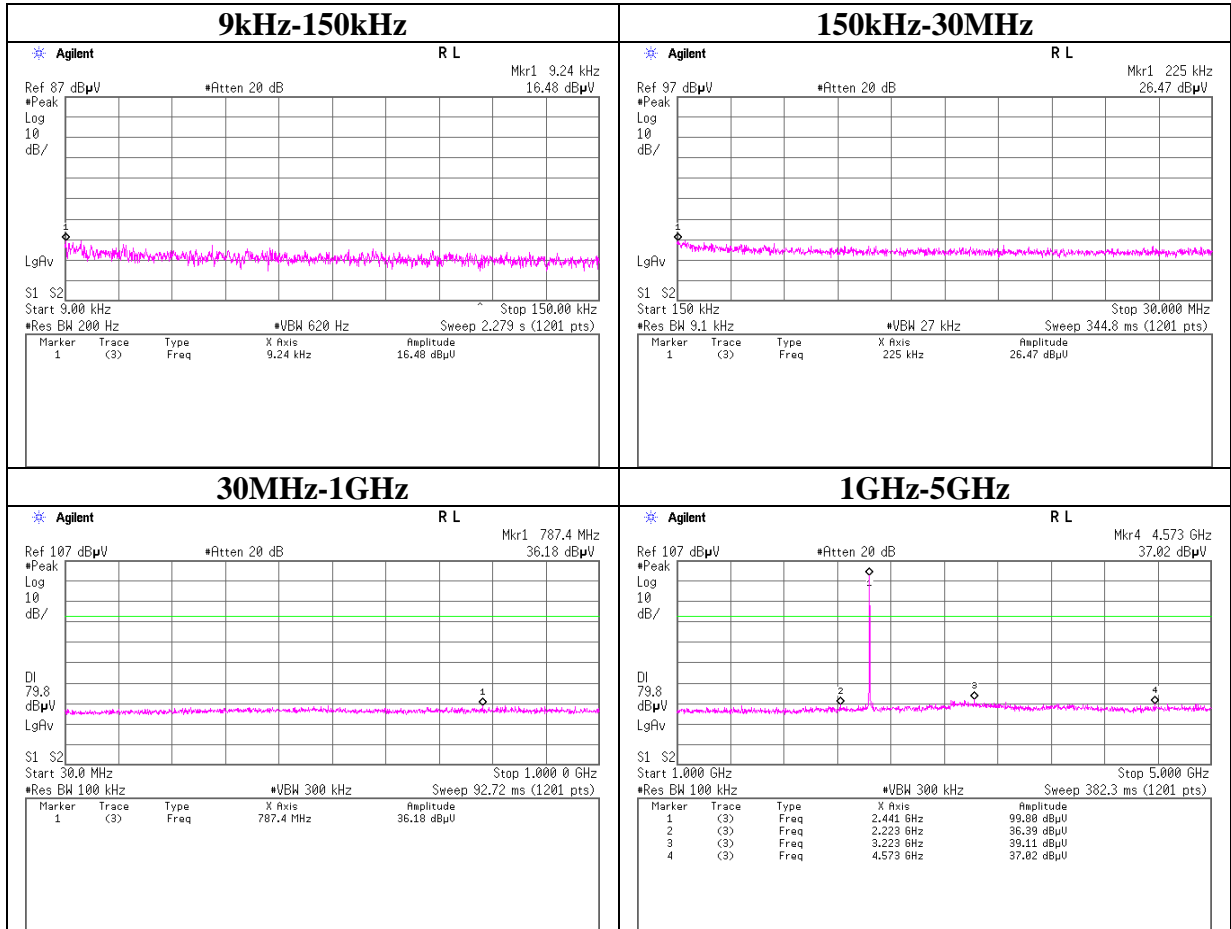
## Conducted Spurious Emission

### Tx DH5 2402MHz



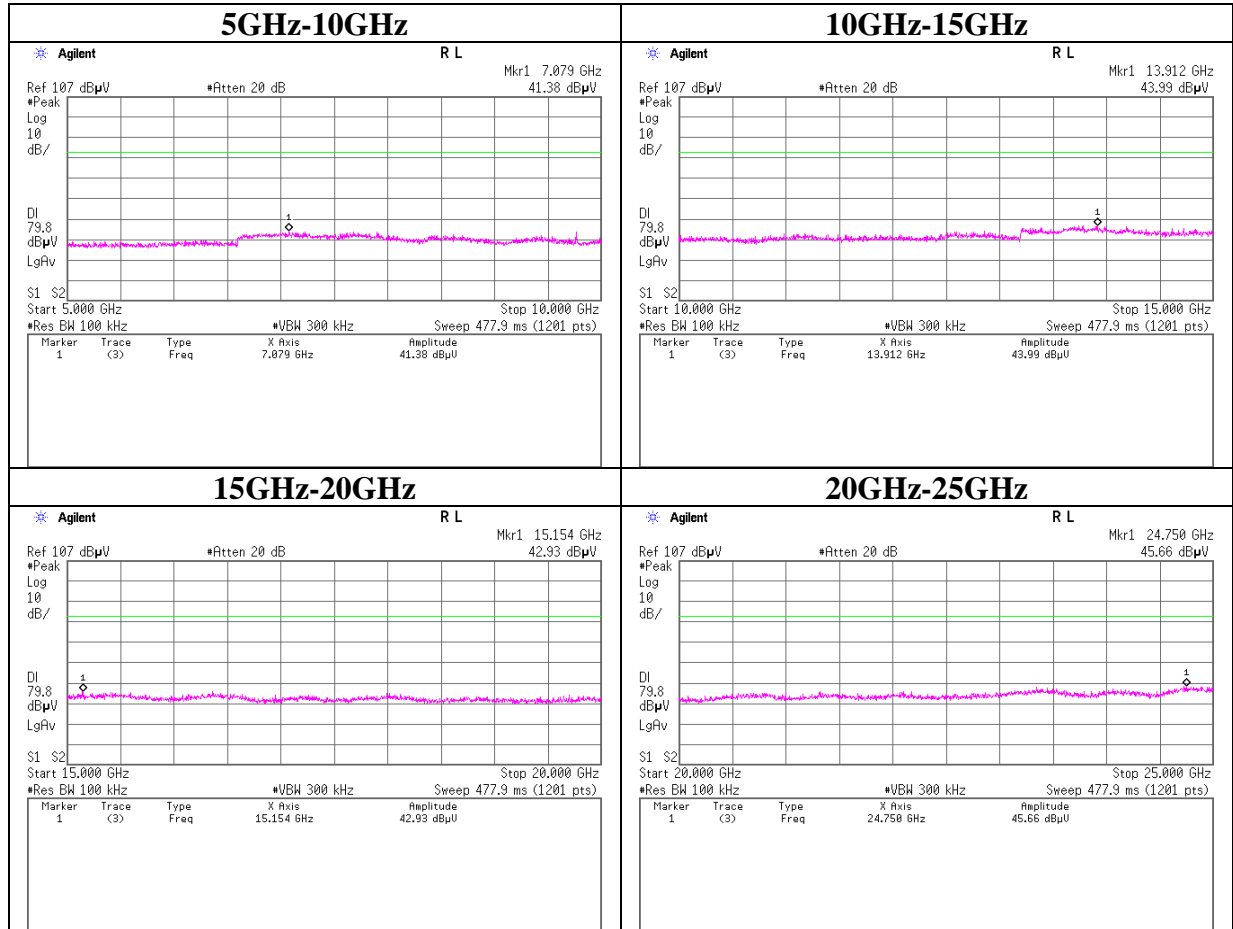
## Conducted Spurious Emission

### Tx DH5 2441MHz



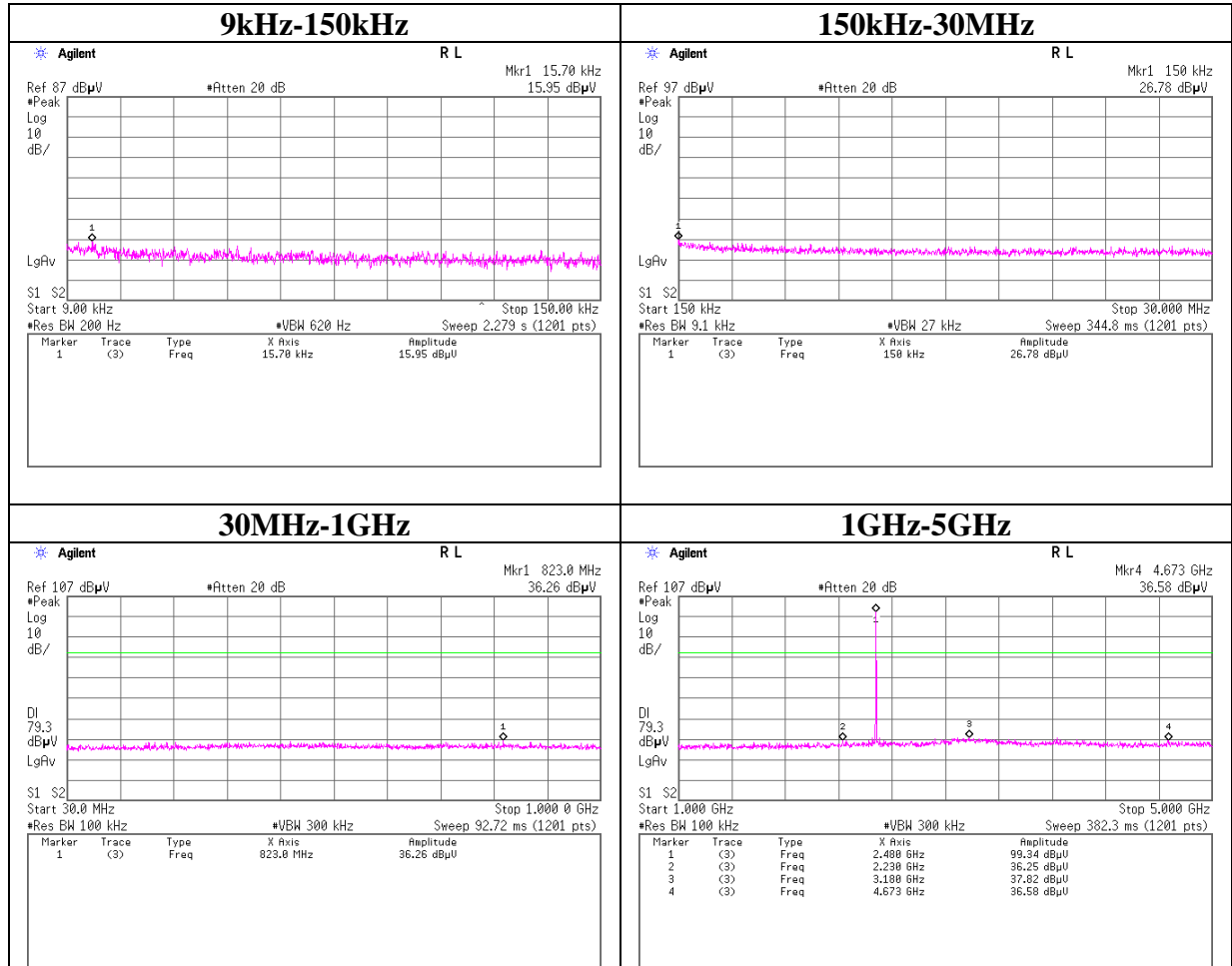
## Conducted Spurious Emission

### Tx DH5 2441MHz



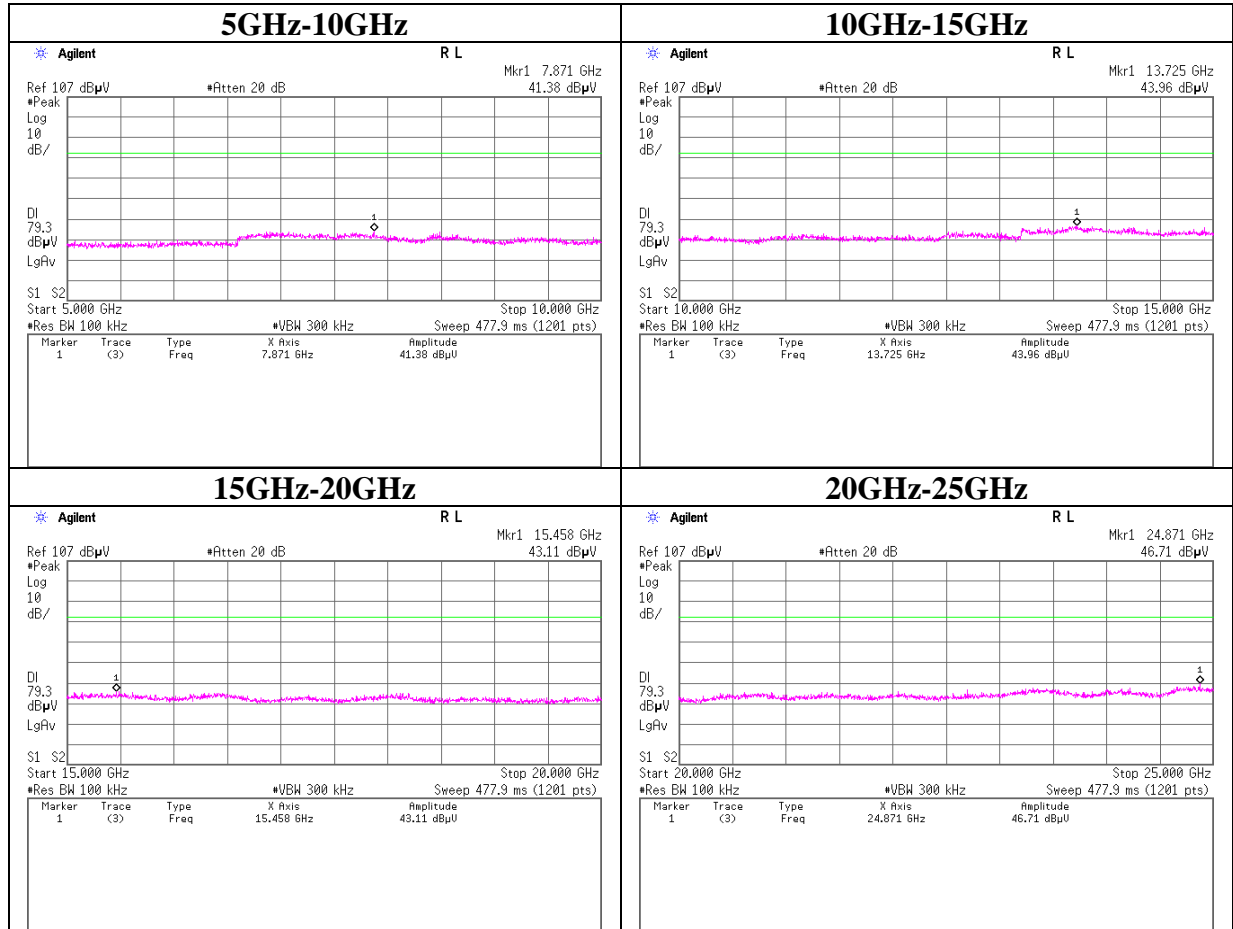
## Conducted Spurious Emission

### Tx DH5 2480MHz



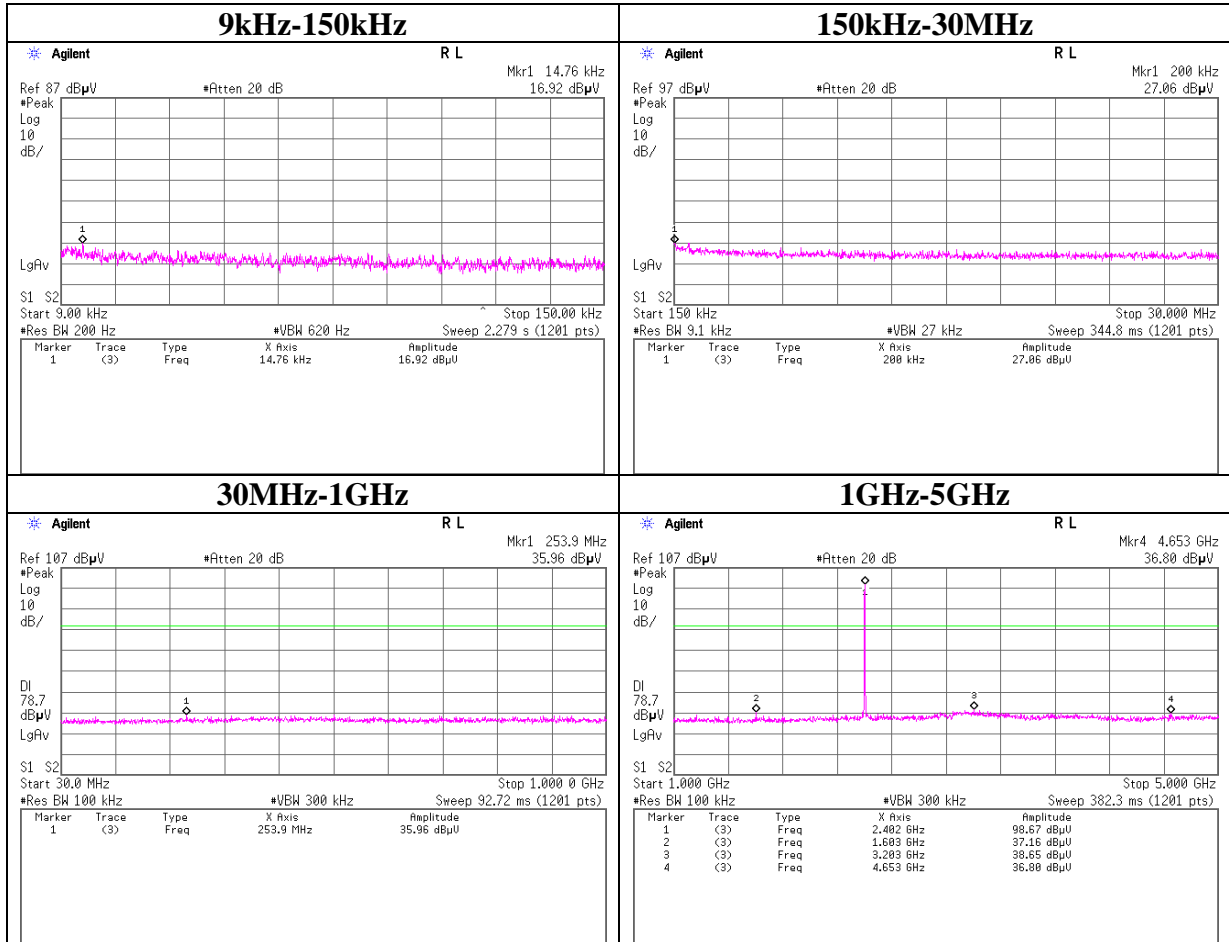
## Conducted Spurious Emission

### Tx DH5 2480MHz



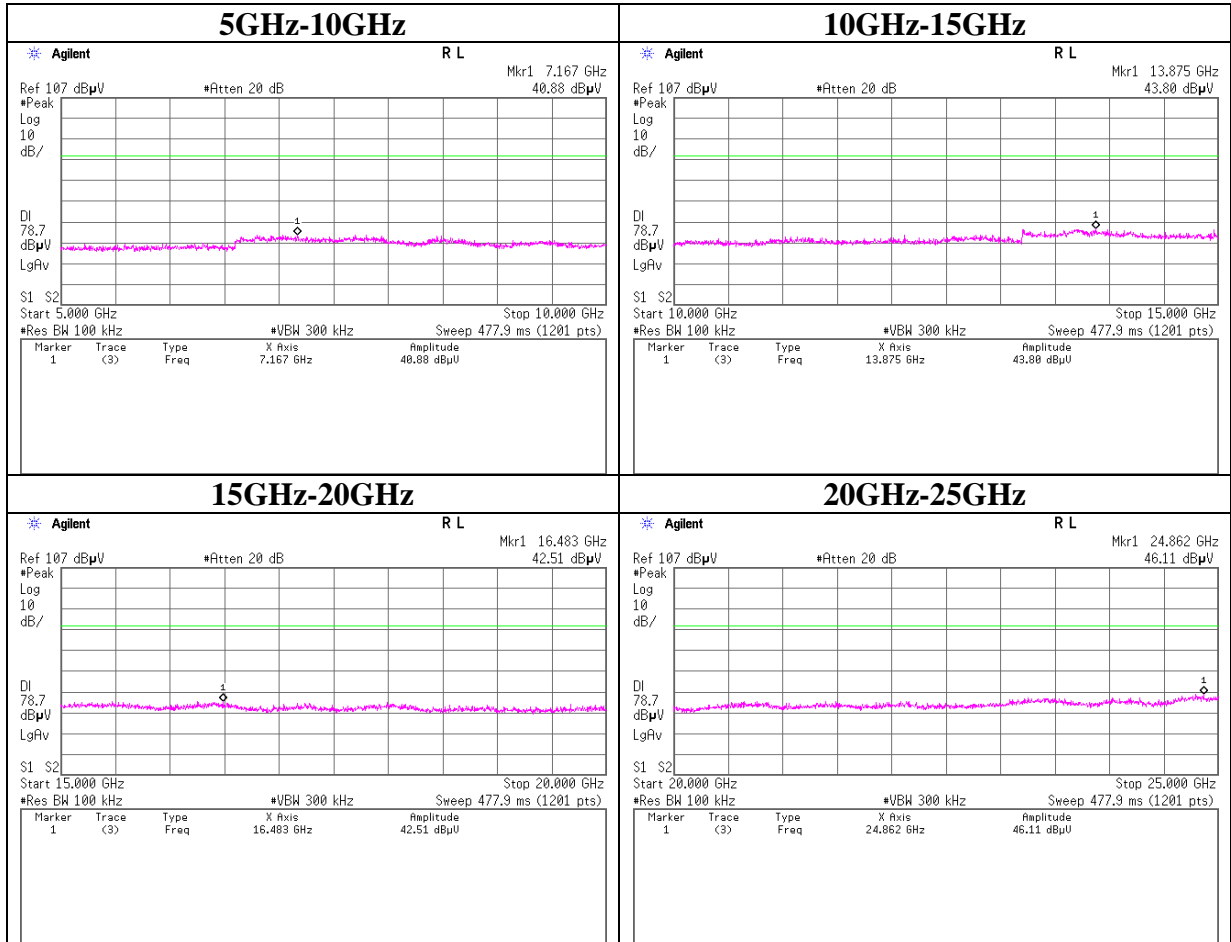
## Conducted Spurious Emission

### Tx 3DH5 2402MHz



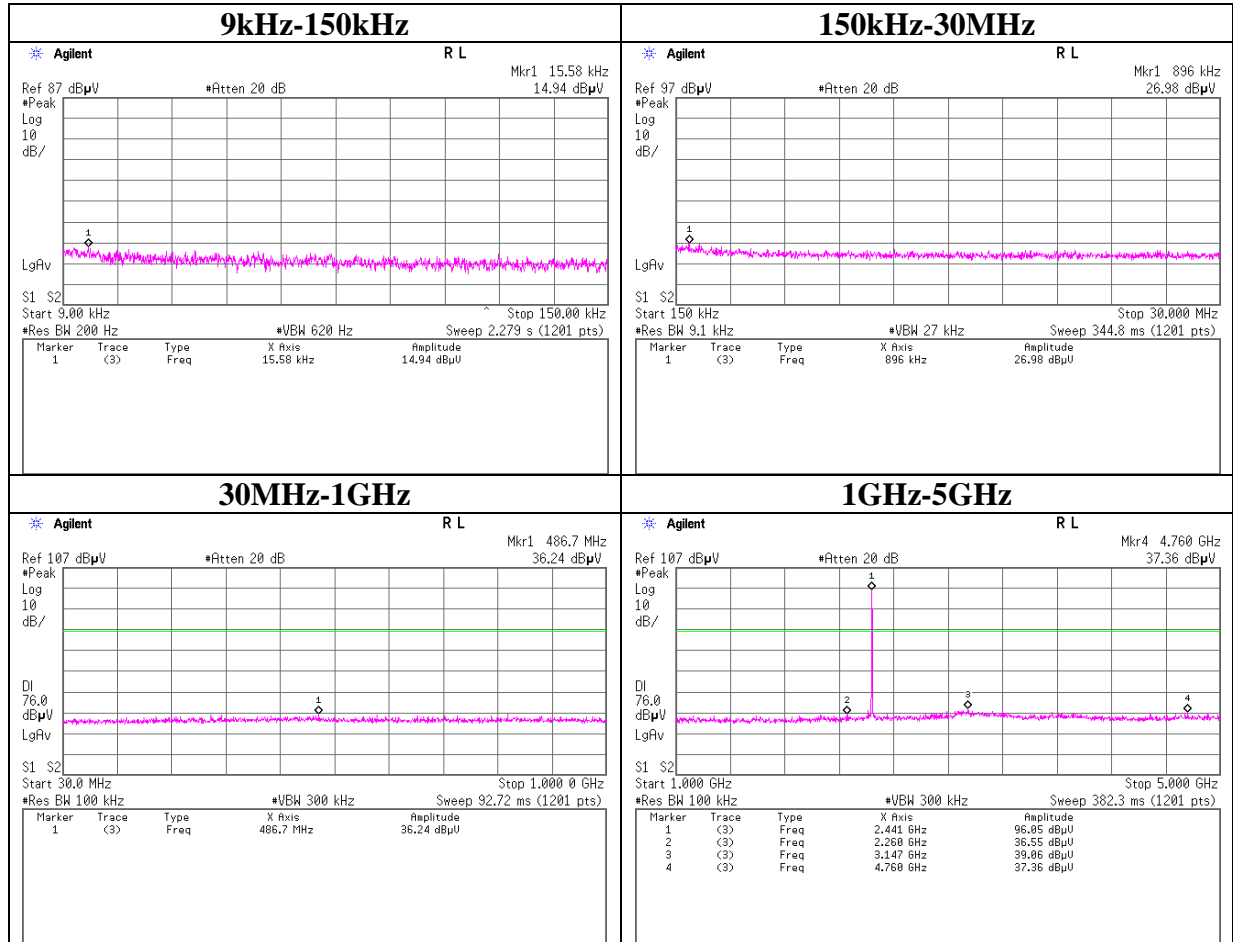
## Conducted Spurious Emission

### Tx 3DH5 2402MHz



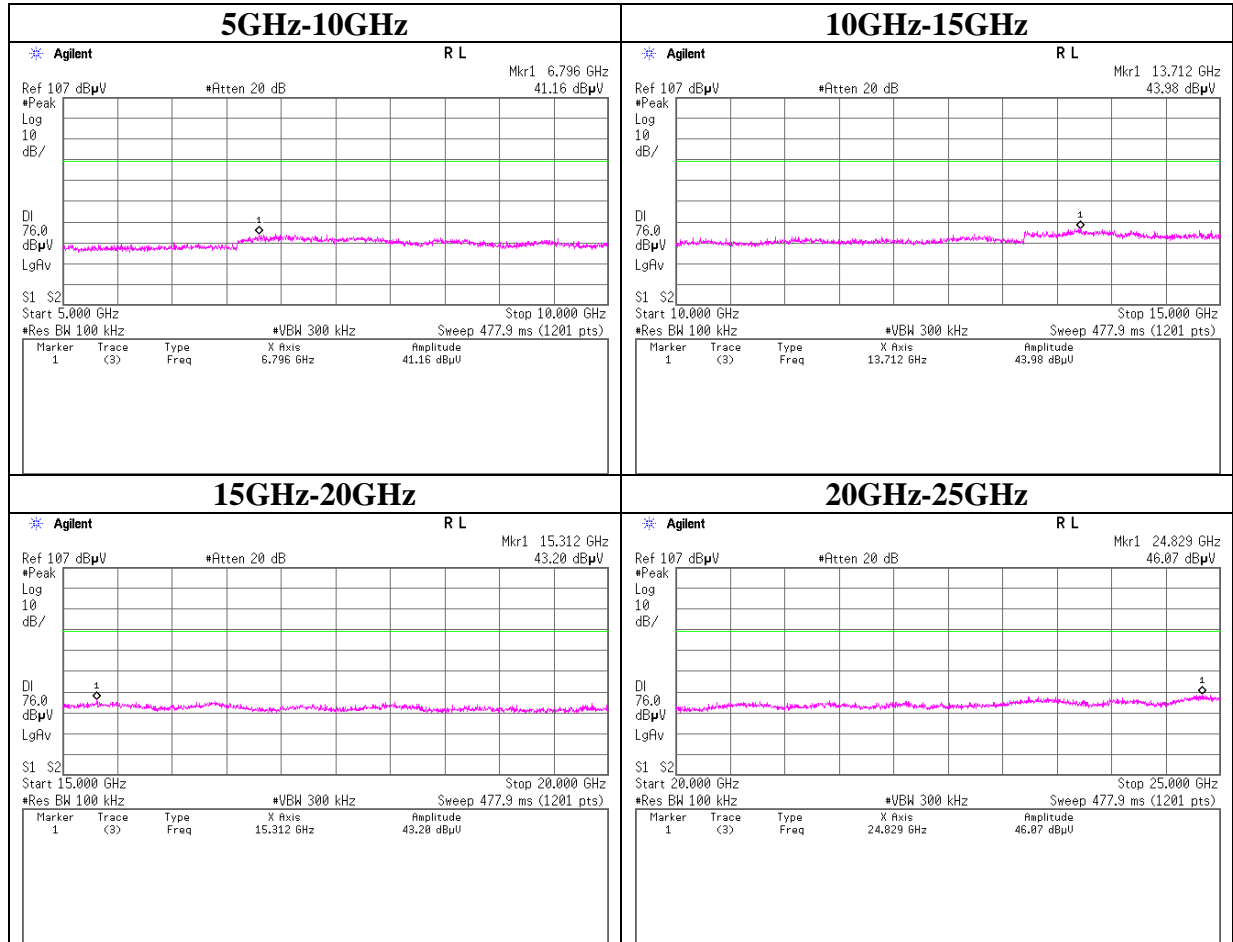
## Conducted Spurious Emission

### Tx 3DH5 2441MHz



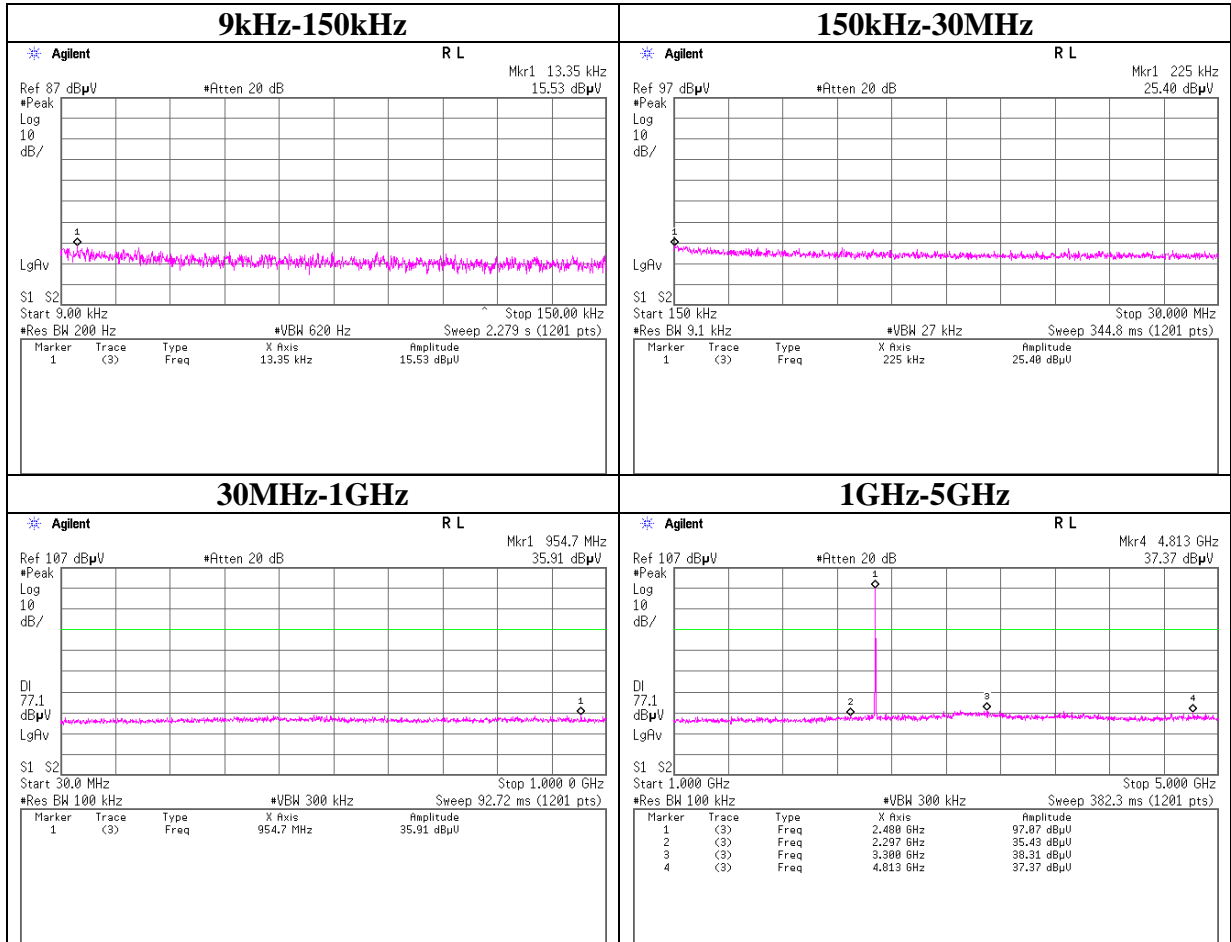
## Conducted Spurious Emission

### Tx 3DH5 2441MHz



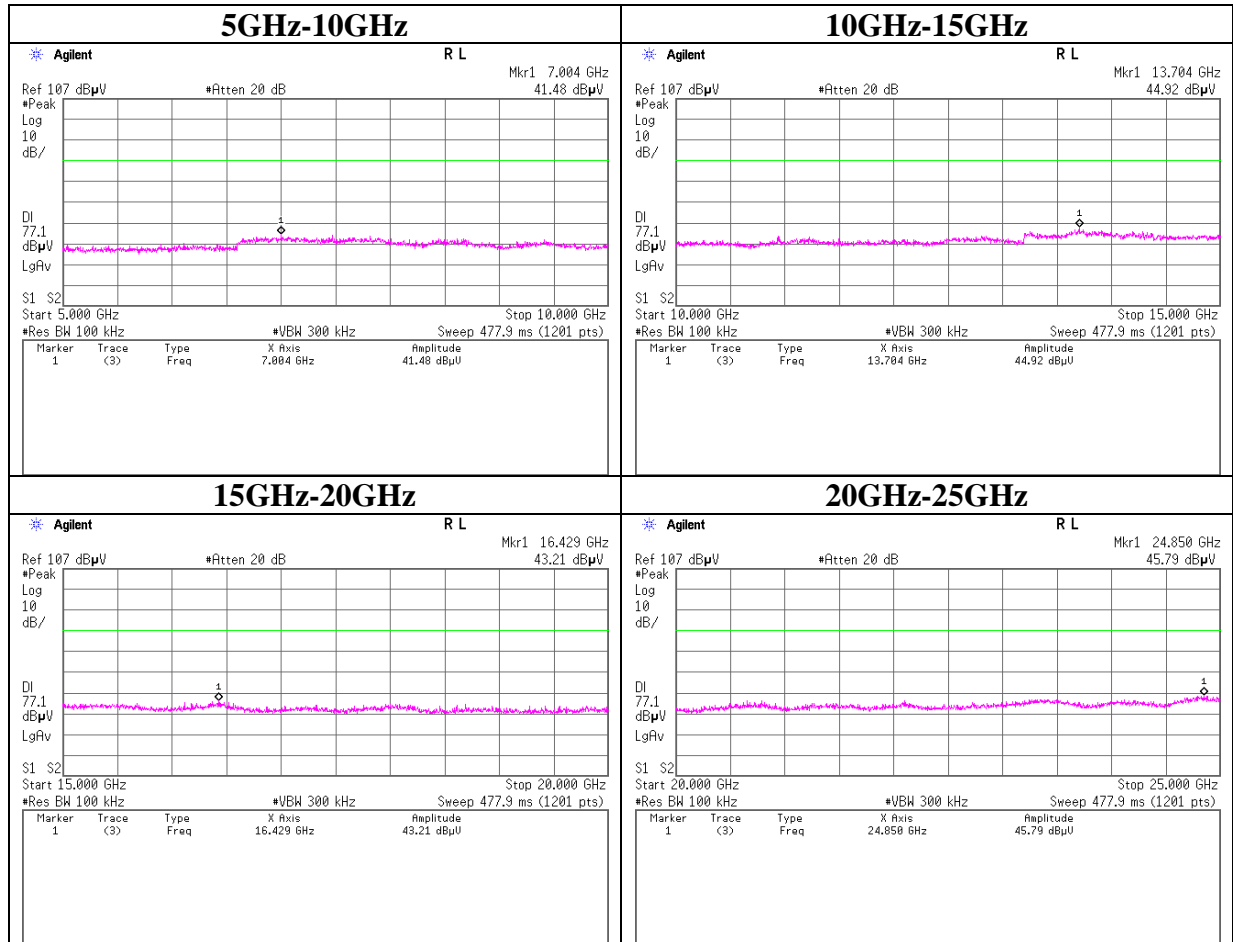
## Conducted Spurious Emission

### Tx 3DH5 2480MHz



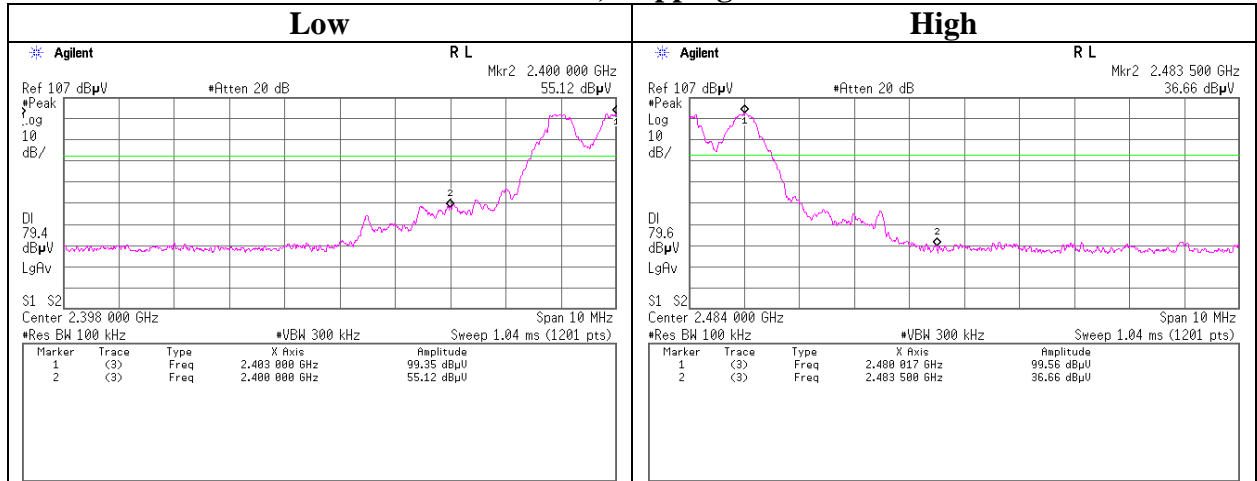
## Conducted Spurious Emission

### Tx 3DH5 2480MHz

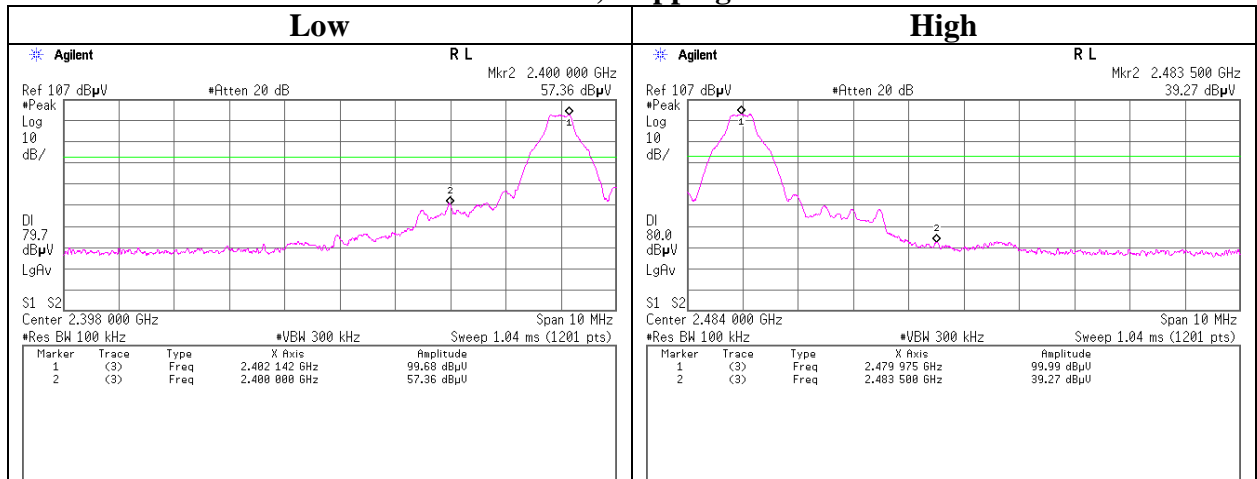


## Conducted Emission Band Edge compliance

### Tx DH5, Hopping on

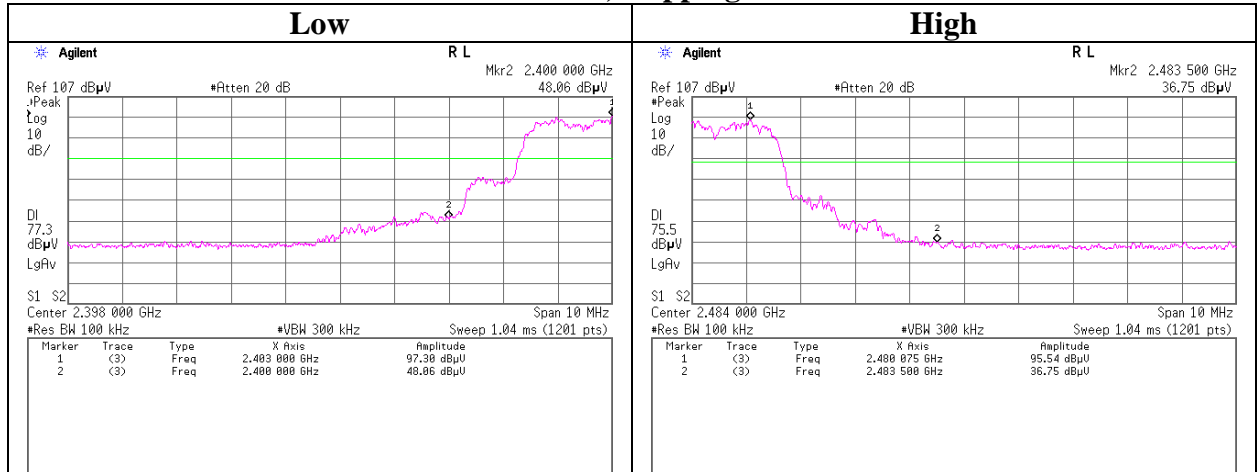


### Tx DH5, Hopping off

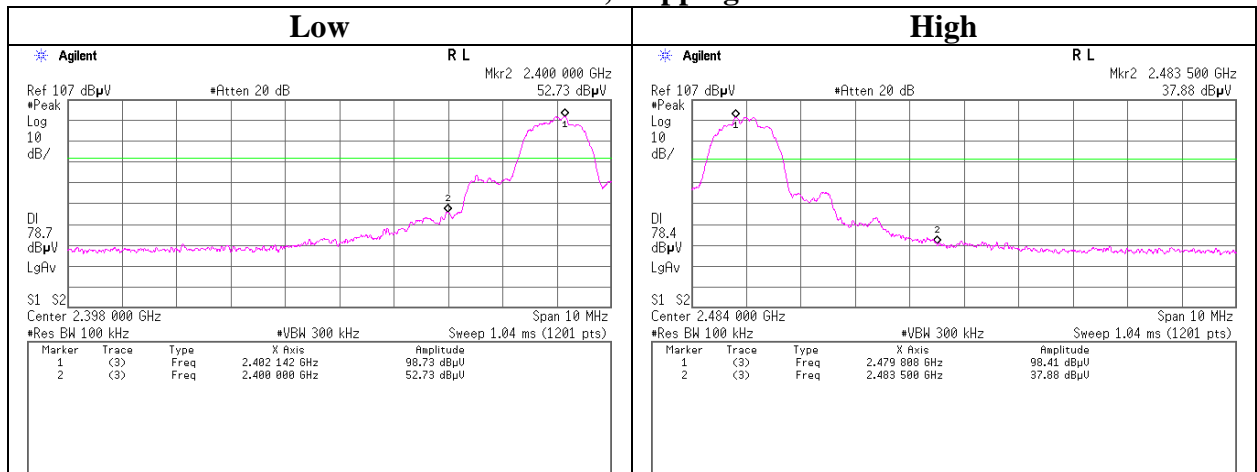


**Conducted Emission Band Edge compliance**

**Tx 3DH5, Hopping on**



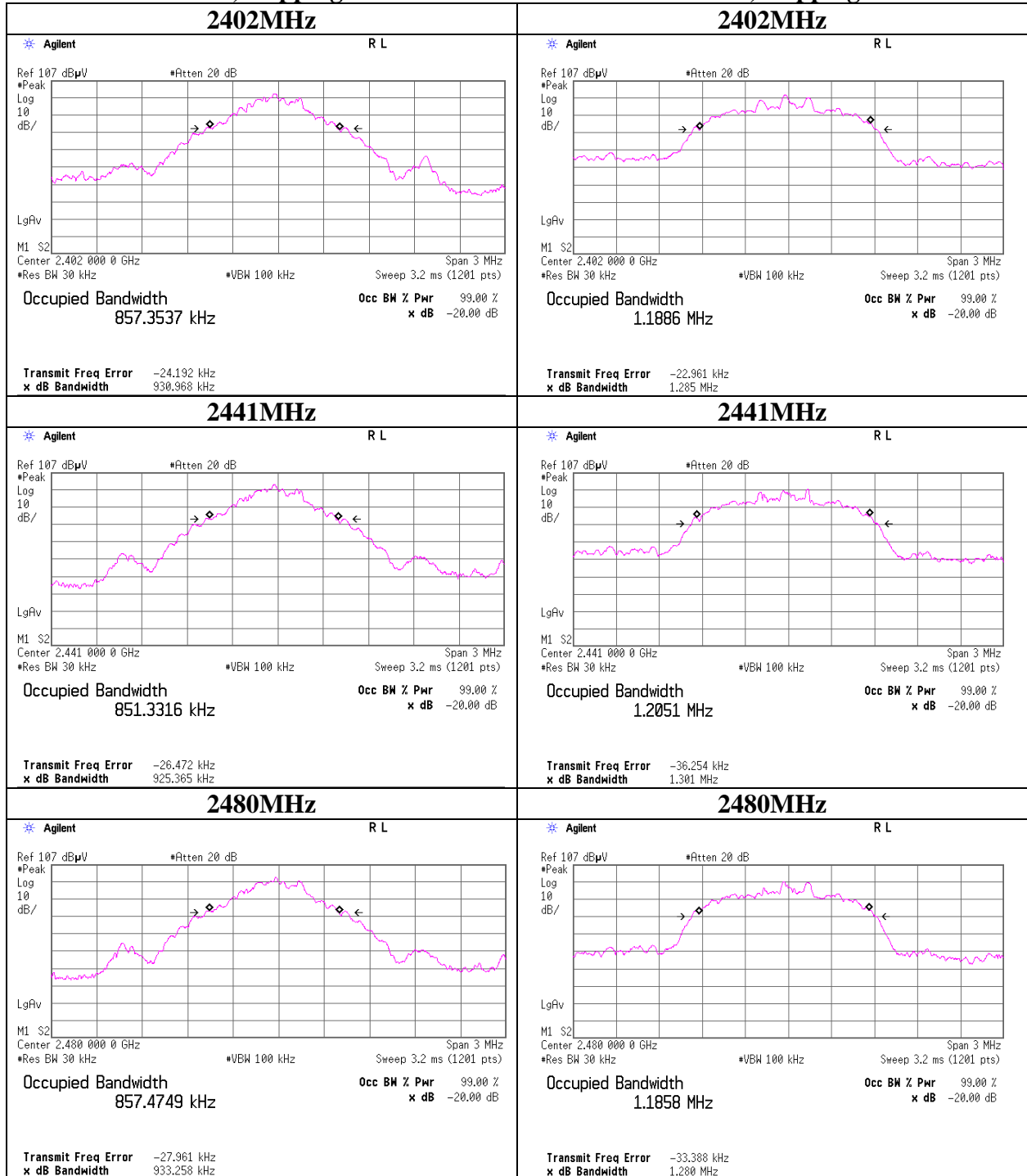
**Tx 3DH5, Hopping off**



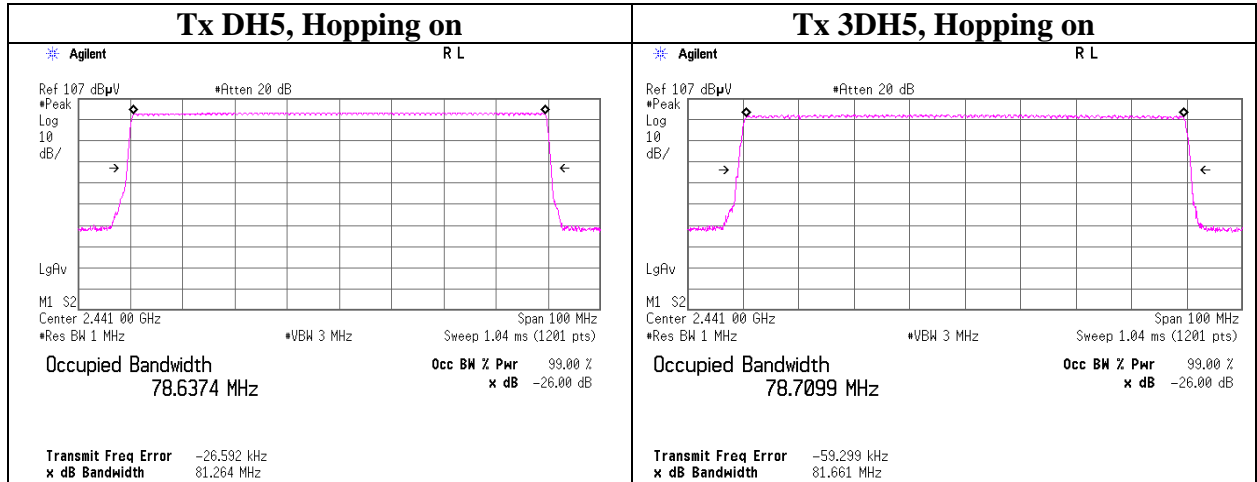
**99% Occupied Bandwidth**

**Tx DH5, Hopping off**

**Tx 3DH5, Hopping off**



### 99% Occupied Bandwidth



## APPENDIX 2: Test instruments

### EMI test equipment

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MAEC-04	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 3m	DA-10005	RE/CE	2012/02/29 * 12
MOS-15	Thermo-Hygrometer	Custom	CTH-180	-	RE/CE	2012/02/06 * 12
MJM-07	Measure	PROMART	SEN1955	-	RE/CE	-
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	RE/CE	-
MSA-10	Spectrum Analyzer	Agilent	E4448A	MY46180655	RE/CE/AT	2012/02/03 * 12
MHA-21	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	9120D-557	RE	2012/08/17 * 12
MCC-141	Microwave Cable	Junkosha	MWX221	1203S212(1m) / 1204S062(5m)	RE	2012/04/23 * 12
MPA-12	MicroWave System Amplifier	Agilent	83017A	MY39500780	RE	2012/03/28 * 12
MCC-79	Microwave Cable 1G-26.5GHz	Suhner	SUCOFLEX104	278923/4	RE	2011/12/08 * 12
MHF-20	High Pass Filter 3.5-18.0GHz	TOKIMEC	TF323DCC	607	RE	2012/09/12 * 12
MHA-17	Horn Antenna 15-40GHz	Schwarzbeck	BBHA9170	BBHA9170307	RE	2012/06/27 * 12
MTR-07	Test Receiver	Rohde & Schwarz	ESCI	100635	CE	2012/04/05 * 12
MLS-07	LISN(AMN)	Schwarzbeck	NSLK8127	8127364	CE	2012/02/09 * 12
MAT-67	Attenuator	JFW Industries, Inc.	50FP-013H2 N	-	CE	2012/01/28 * 12
MCC-113	Coaxial cable	Fujikura/Suhner/TSJ	5D-2W(10m)/ SFM141(5m)/ 421-010(1m)/ suciform141-PE(1m)/ RFM-E121(Switcher)	-/04178	CE	2012/07/12 * 12
MOS-04	Digital Humidity Indicator	N.T	NT-1800	MOS04	AT	2012/02/06 * 12
MPSE-18	Power sensor	Anritsu	MA2411B	0738174	AT	2011/11/07 * 12
MPM-13	Power Meter	Anritsu	ML2495A	0824014	AT	2011/11/07 * 12
MCC-103	Microwave Cable	Hirose Electric	U.FL-2LP-066J1-A(200)	-	AT	2012/06/27 * 12
MAT-25	Attenuator(10dB) (above1GHz)	Agilent	8493C	71642	AT	2012/06/27 * 12
MTR-07	Test Receiver	Rohde & Schwarz	ESCI	100635	RE	2012/04/05 * 12
MBA-05	Biconical Antenna	Schwarzbeck	BBA9106	1302	RE	2012/11/18 * 12
MLA-08	Logperiodic Antenna	Schwarzbeck	UKLP9140-A	N/A	RE	2012/11/18 * 12
MCC-50	Coaxial Cable	UL Japan	-	-	RE	2012/06/01 * 12
MAT-68	Attenuator	Anritsu	MP721B	6200961025	RE	2012/11/21 * 12
MPA-14	Pre Amplifier	SONOMA INSTRUMENT	310	260833	RE	2012/03/05 * 12

**The expiration date of the calibration is the end of the expired month.**

**All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.**

**As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.**

**Test Item: CE: Conducted Emission  
RE: Radiated Emission  
AT: Antenna Terminal Conducted test**

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